

ERATO Meeting Nov.17.2015

High-precision 3-D surface measurement
using multi-wavelength digital holography
referenced by optical frequency comb

By

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Principle

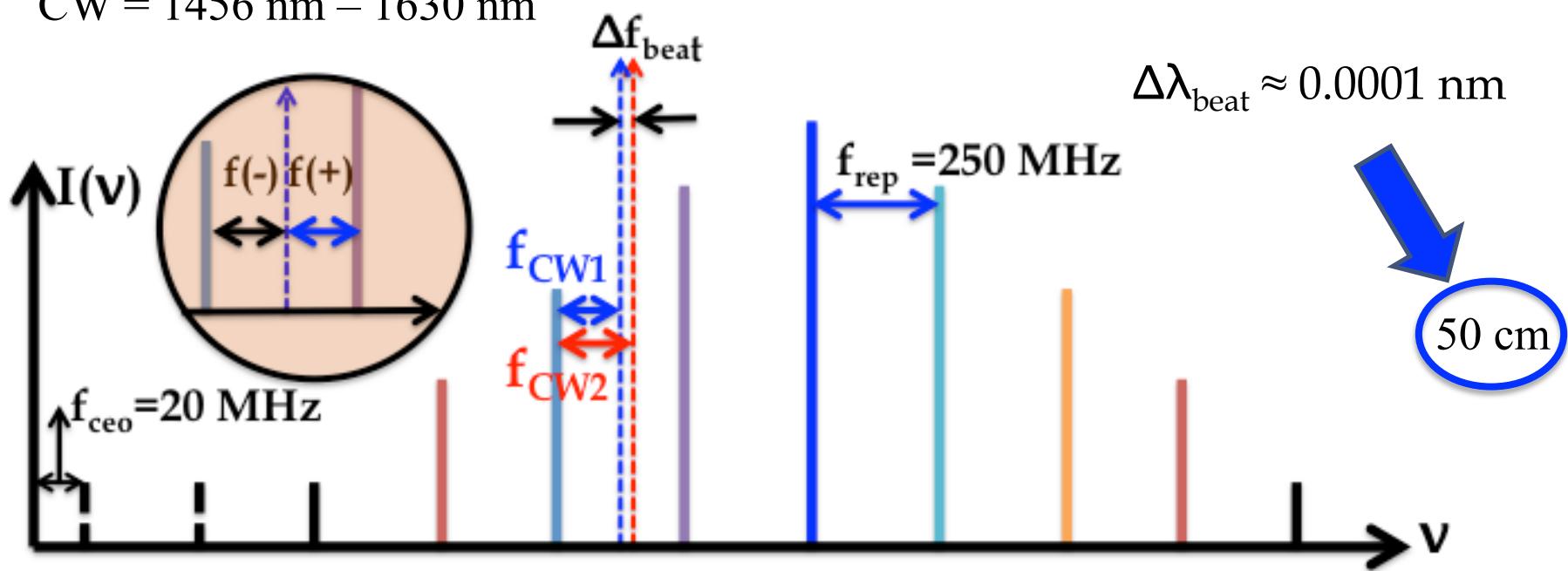
Merits:

- 1- High-precision (referenced to the FC of the fiber laser which is stabilized to the Rb atomic clock of 10^{-12} uncertainty)
- 2- Large stepped structures (by varying the repetition rate of femtosecond pulses)
- 3- Does not need phase unwrapping

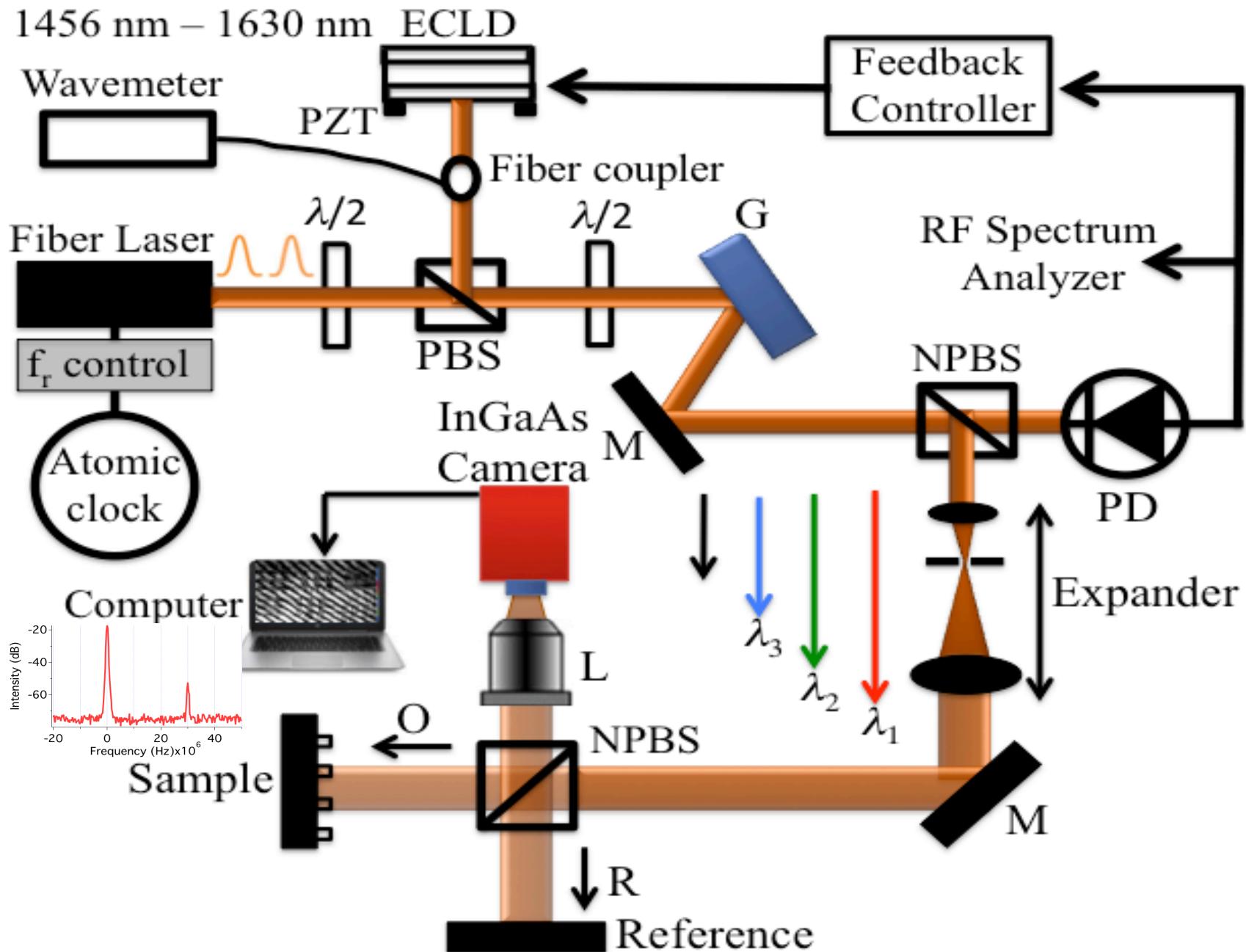
Demerits:

- 1-Not in real-time

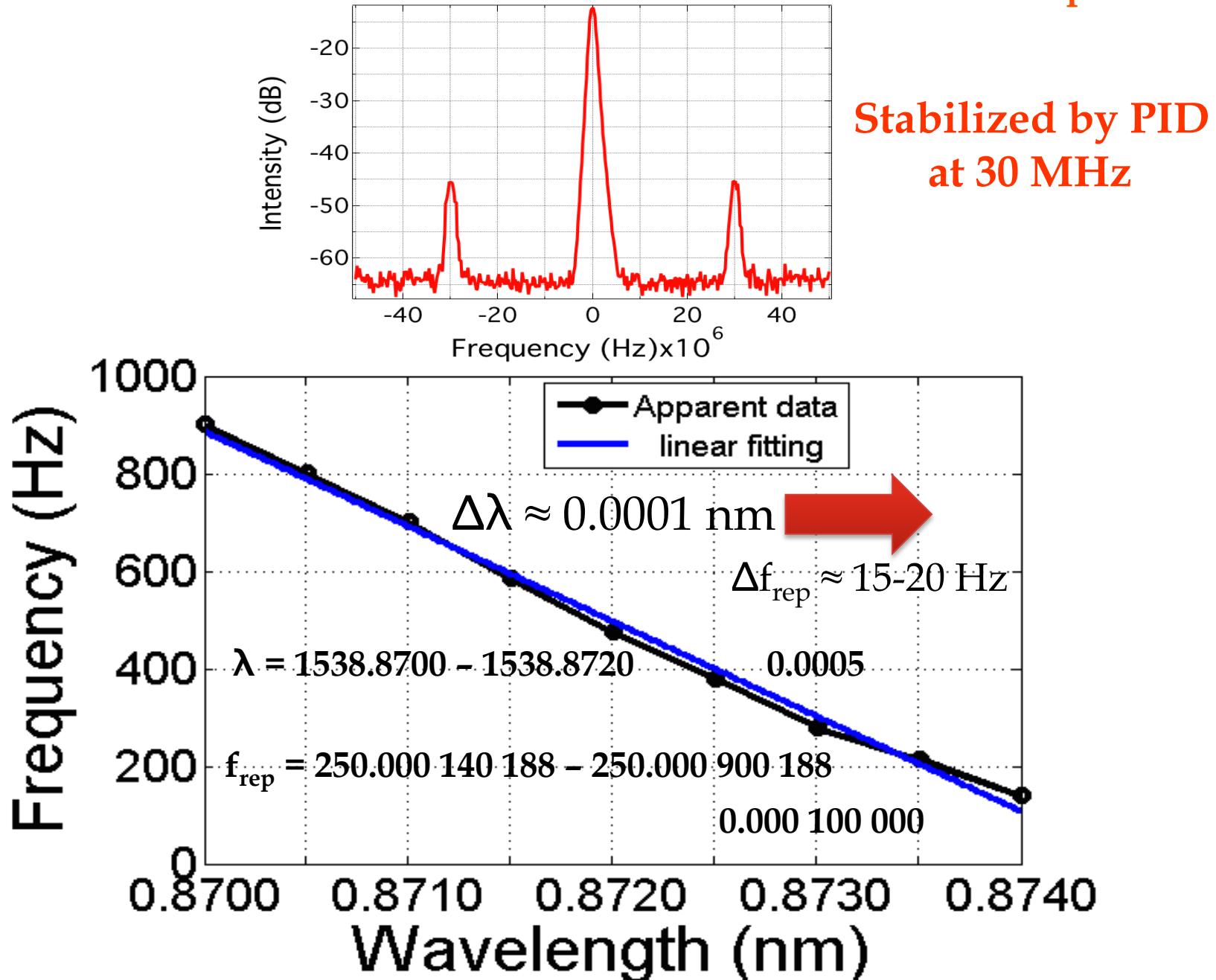
CW = 1456 nm – 1630 nm



Optical setup

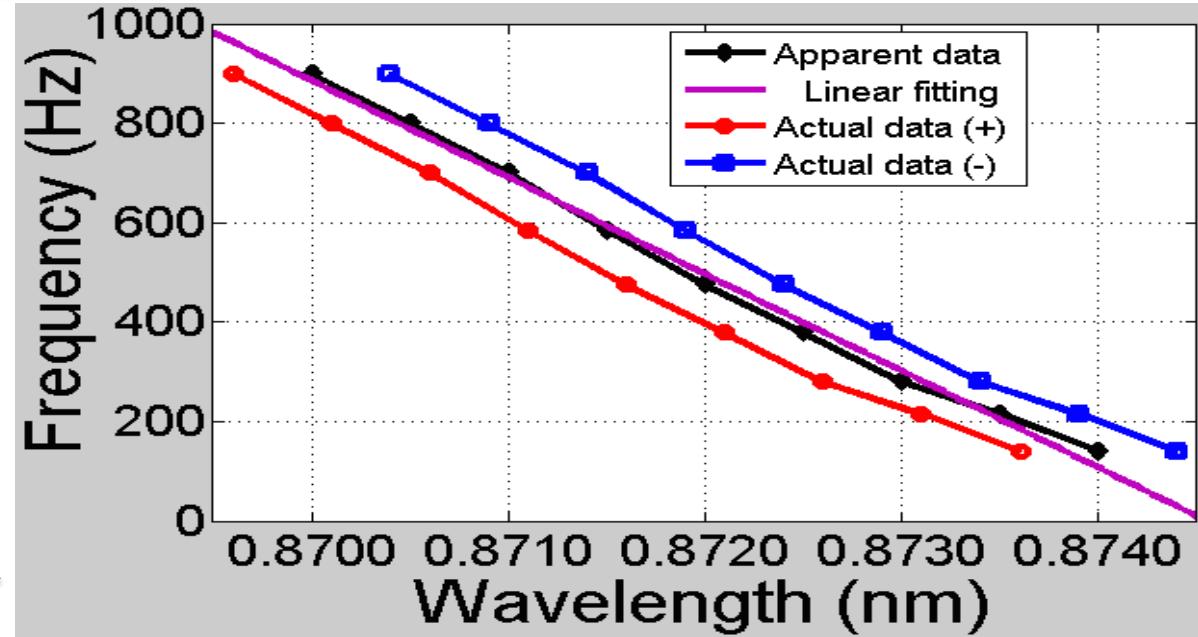
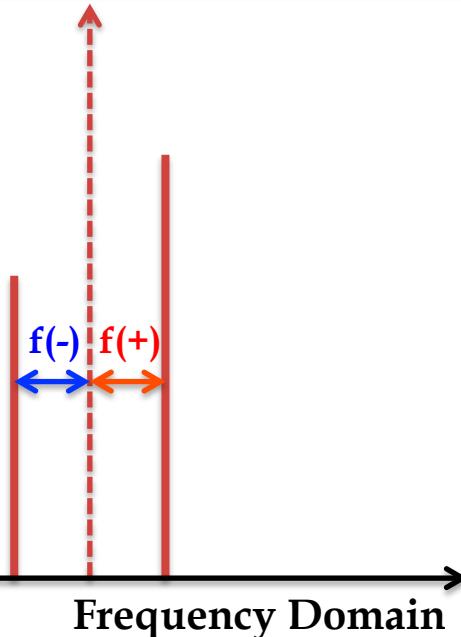


Results: calibration, wavelength vs. f_{rep}



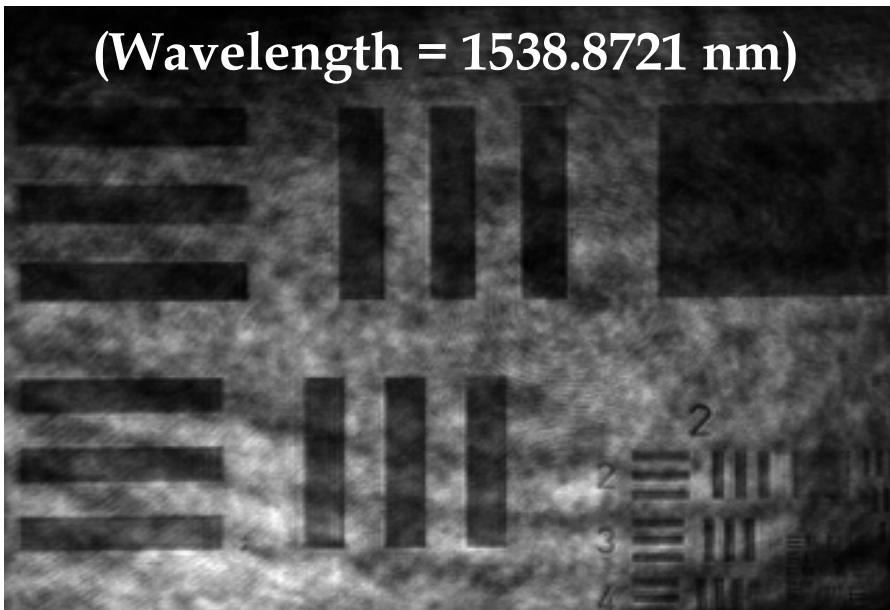
Actual and apparent values of wavelengths (0.0005)

| | | | | | | | |
|-----------------|-----------------|-----------|-----------------|-----------|-----------|-----------|---|
| App. (nm) | 1538.8700 | 1538.8705 | 1538.8710 | 1538.8715 | 1538.8720 | 1538.8725 | 1538.8730 |
| Actual (+nm) | 1538.8696 | 1538.8701 | 1538.8706 | 1538.8711 | 1538.8716 | 1538.8721 | 1538.8726 |
| Actual (-nm) | 1538.8704 | 1538.8709 | 1538.8714 | 1538.8719 | 1538.8724 | 1538.8729 | 1538.8734 |
| f_{rep} (MHz) | | | | 250.000 | | | |
| | 900 188 | 800 188 | 700 188 | 585 188 | 475 188 | 380 188 | 280 188 |
| App. (nm) | 1538.8735 | | 1538.8740 | | | | Diff. = ± 0.0004 nm |
| Actual (+nm) | 1538.8731 | | 1538.8736 | | | | |
| Actual (-nm) | 1538.8739 | | 1538.8744 | | | | $f(\pm) = n_0 f_{rep} \pm f_{ceo} \pm f_{beat}$ |
| f_{rep} (MHz) | 250.000 215 188 | | 250.000 140 188 | | | | |

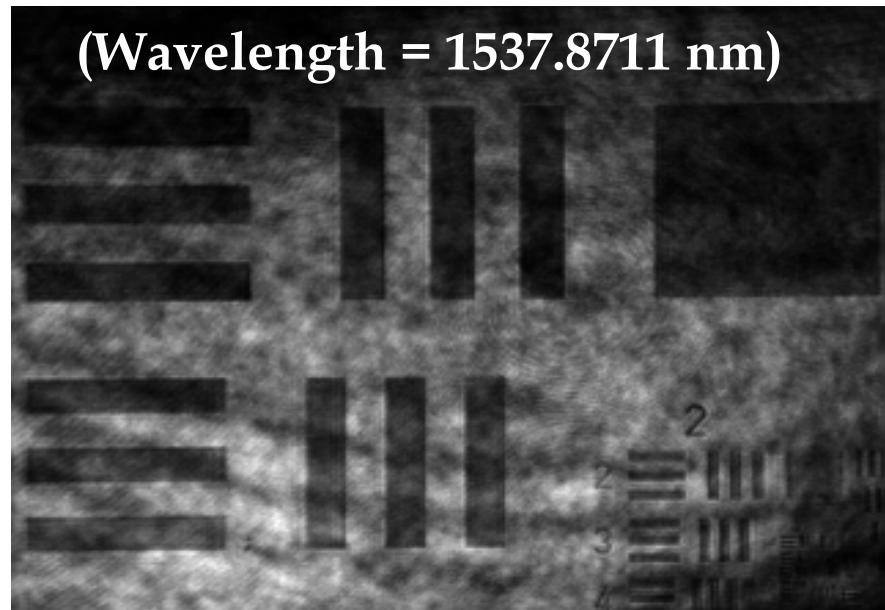


1-1. USF object

(Wavelength = 1538.8721 nm)



(Wavelength = 1537.8711 nm)



Corrected

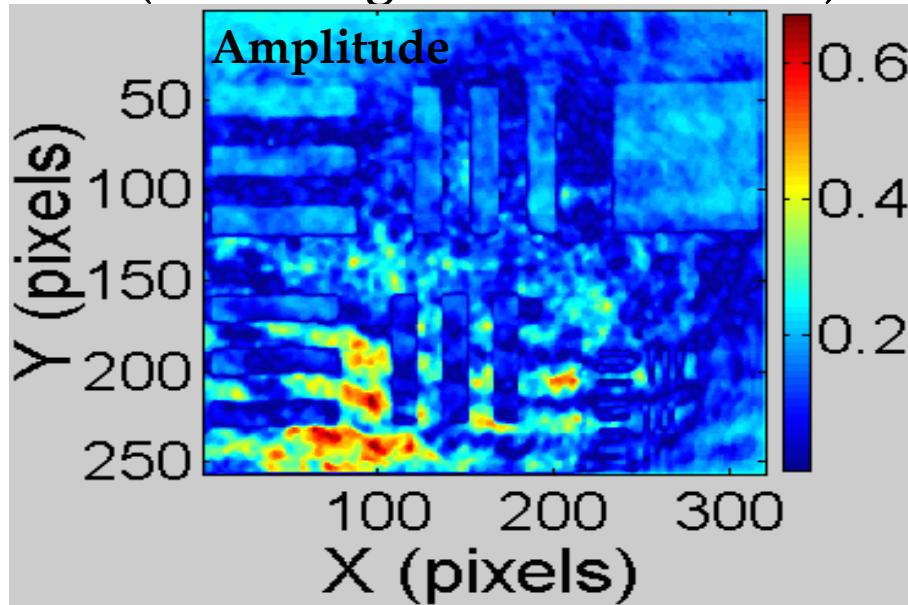


Corrected

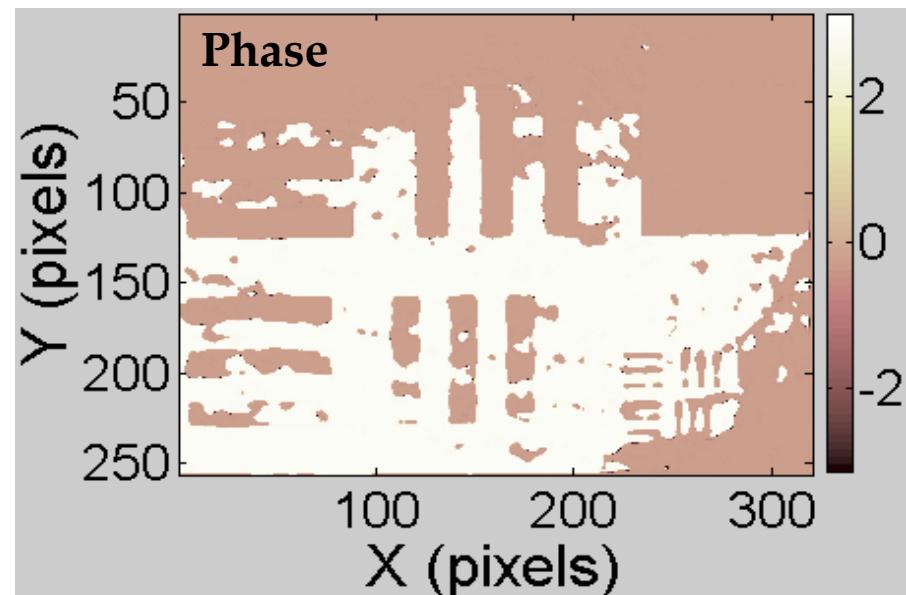
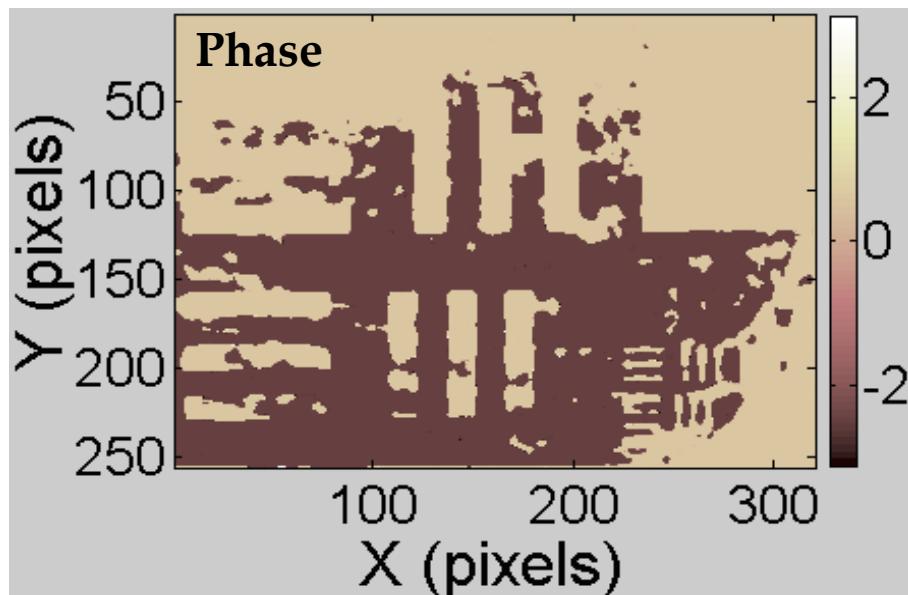
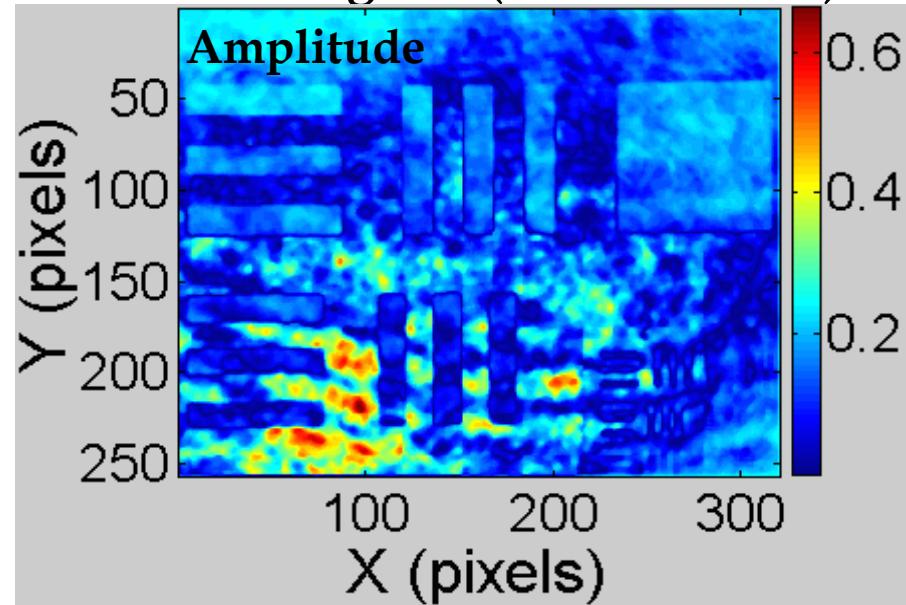


1-1. Reconstruction (original)

(Wavelength = 1538.8721 nm)

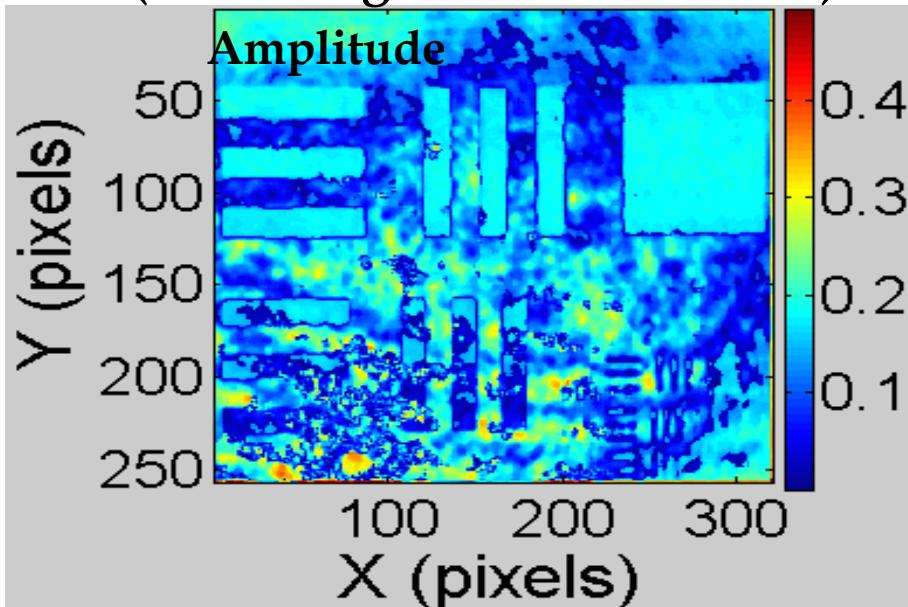


Wavelength = (1537.8711 nm)

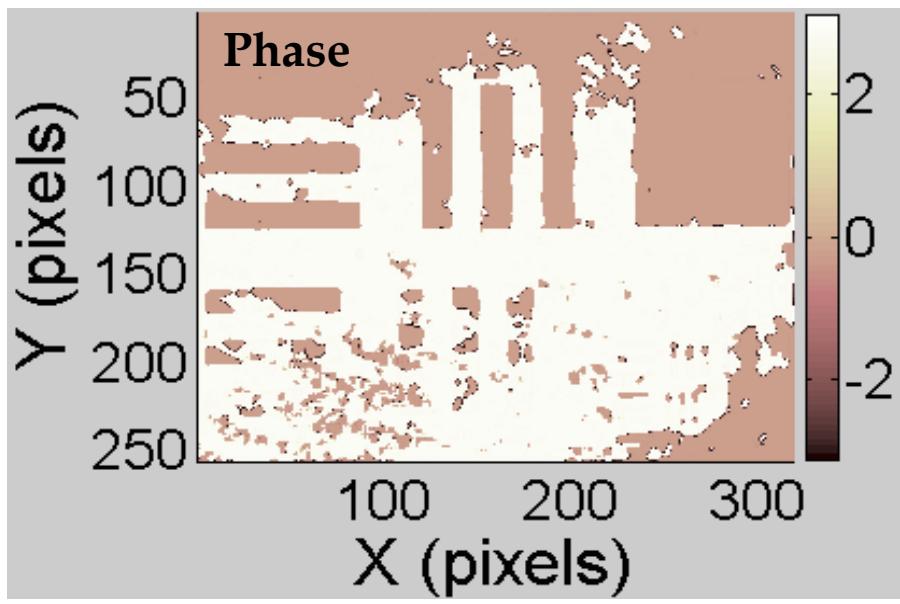
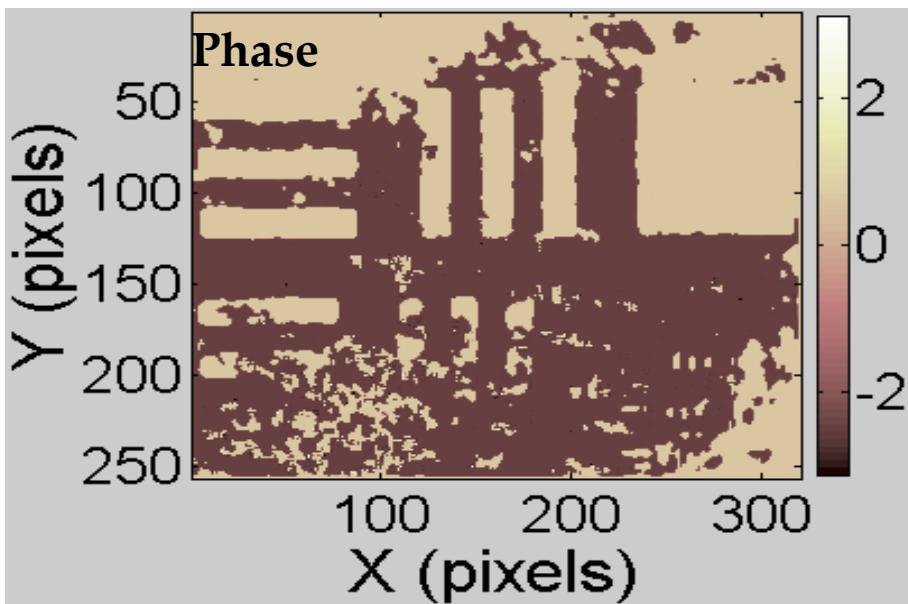
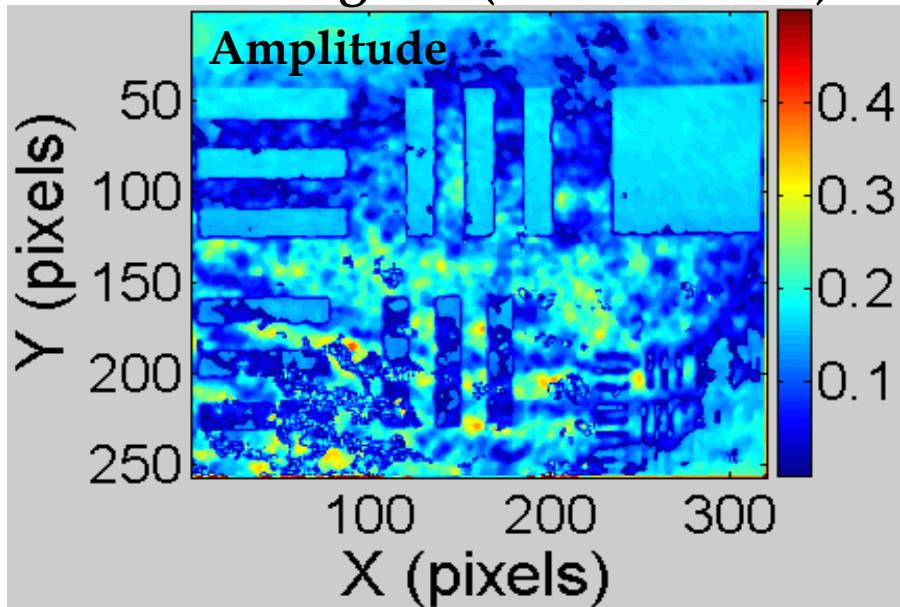


1-1. Reconstruction (corrected)

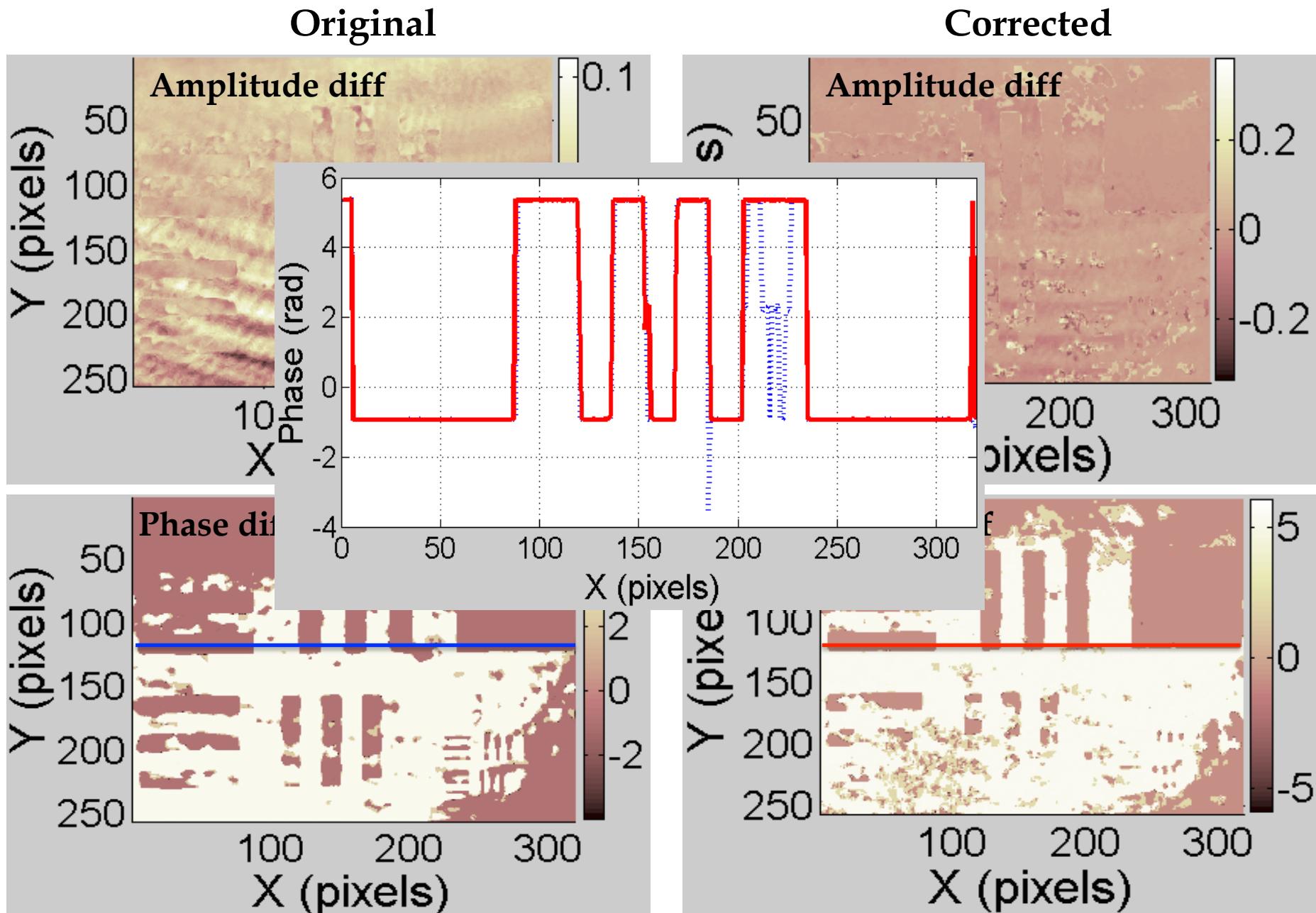
(Wavelength = 1538.8721 nm)



Wavelength = (1537.8711 nm)

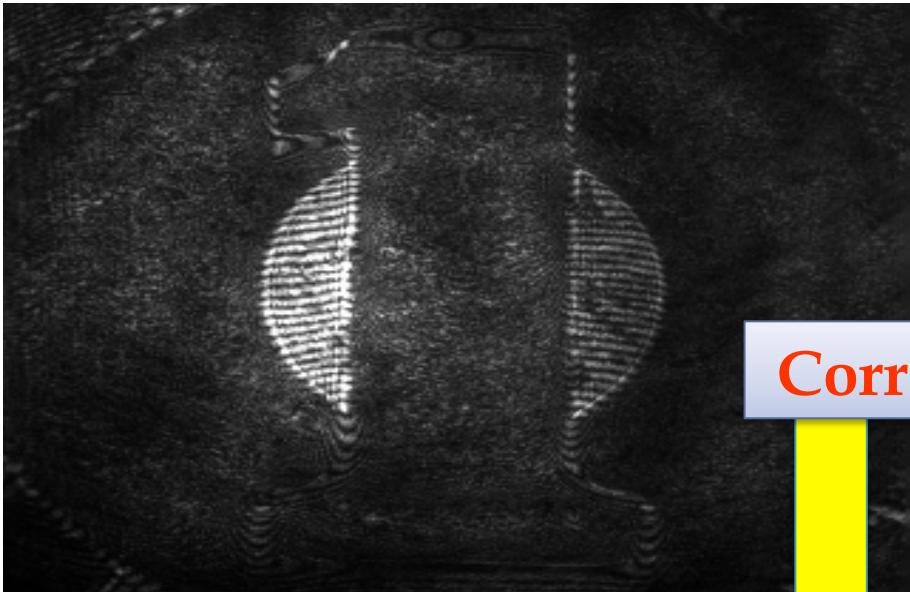


1-1. Differences (amplitudes & phases)

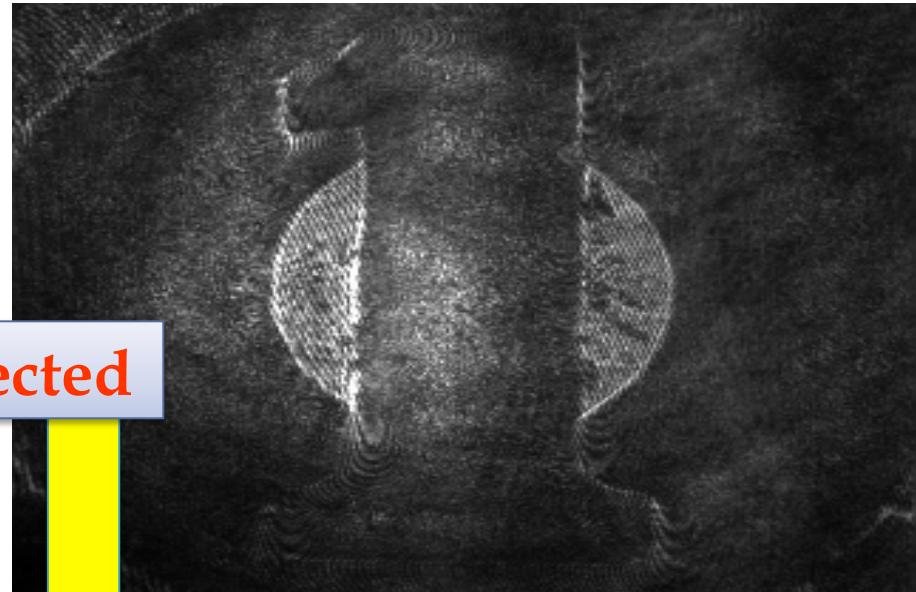


1-2. Rough object (Japanese 1 yen coin)

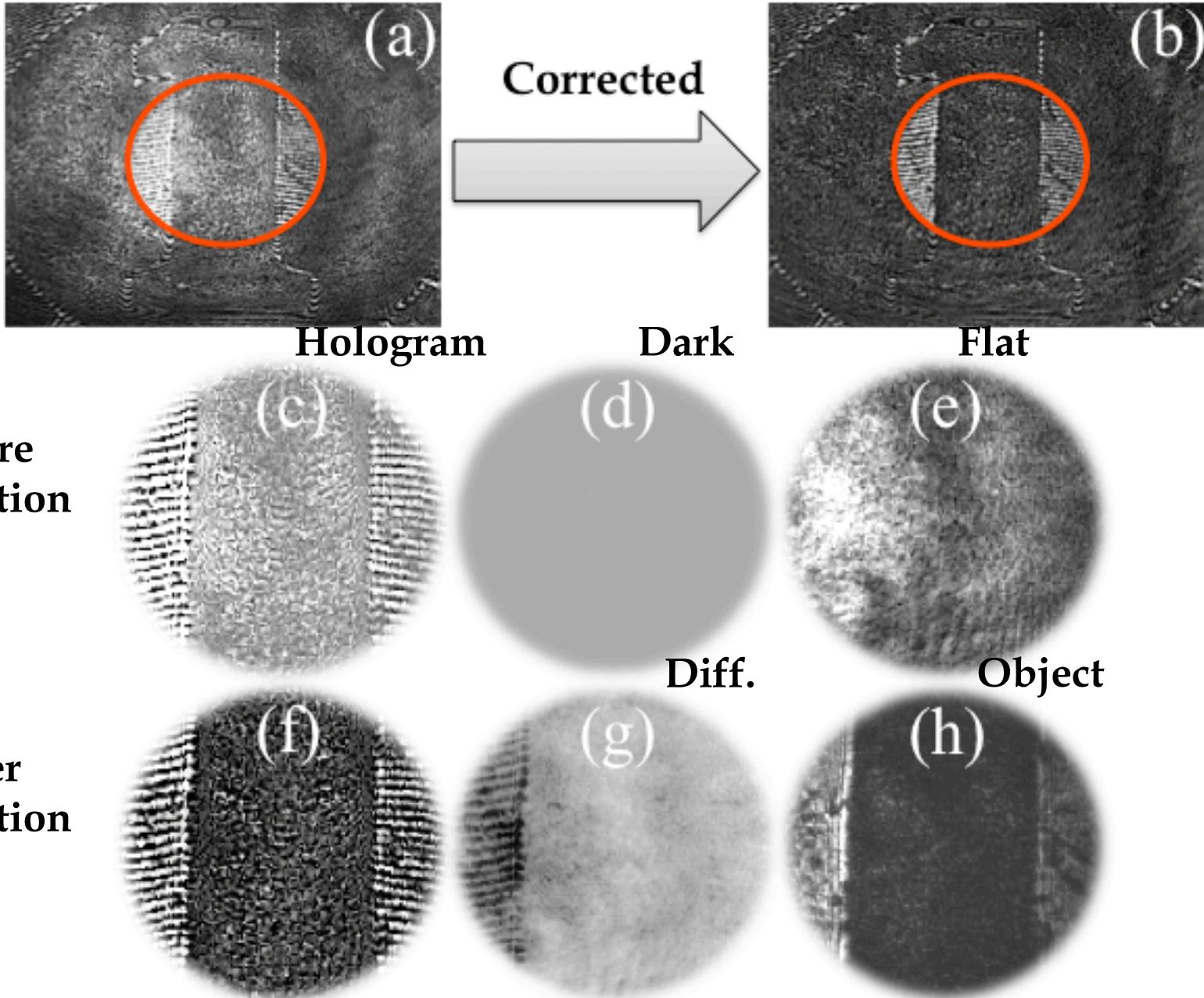
1542.7661 nm



1534.8211 nm

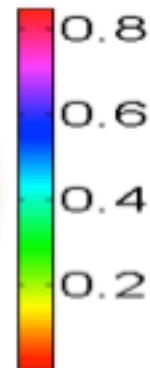
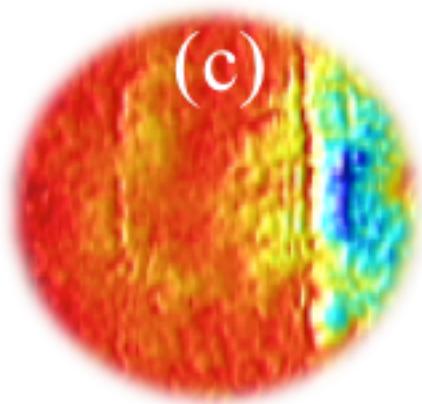
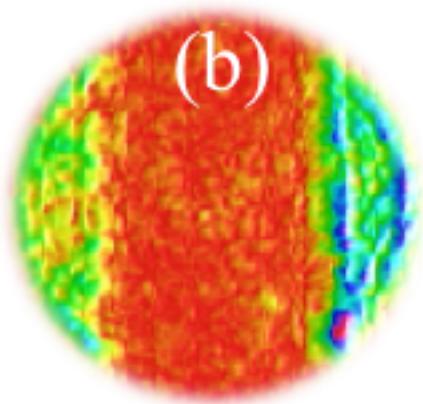
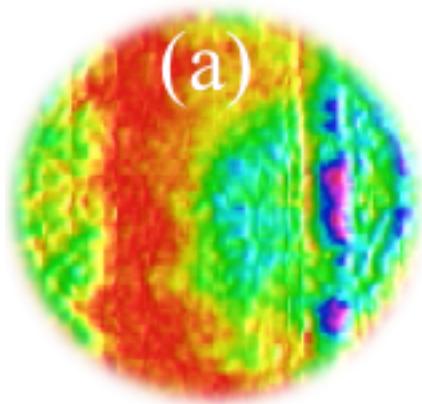


1-2. Hologram correction

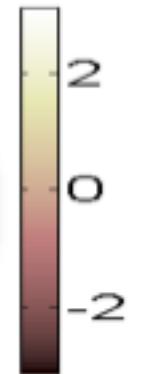
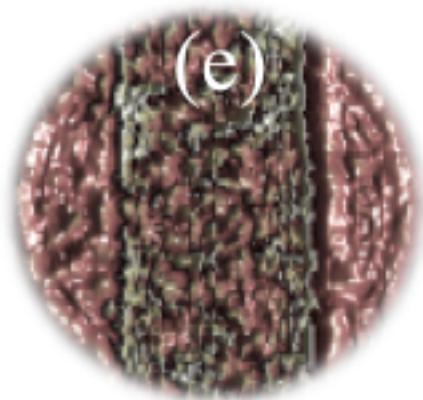
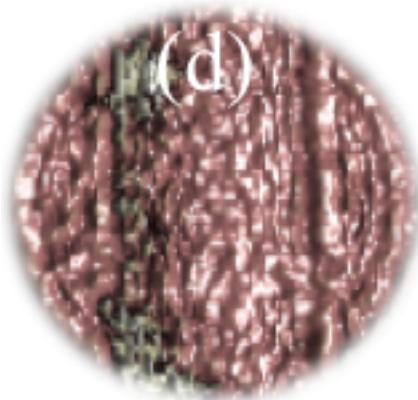


1-2. Impact of noise on reconstruction

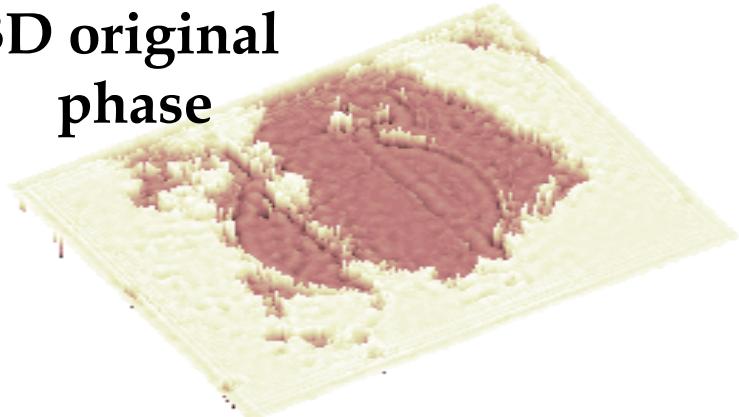
Amplitude



Phase



3D original
phase

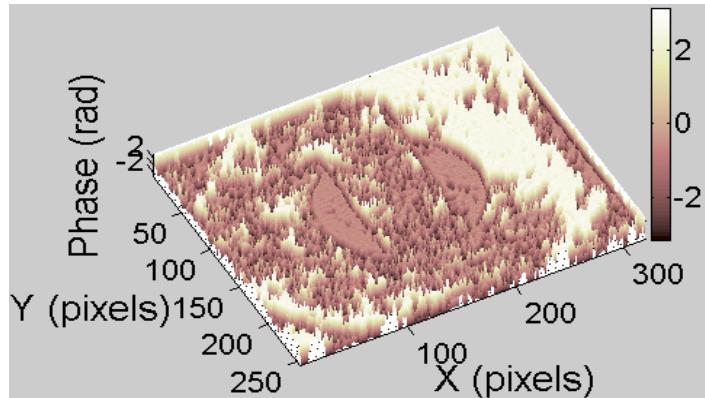


3D corrected
Phase

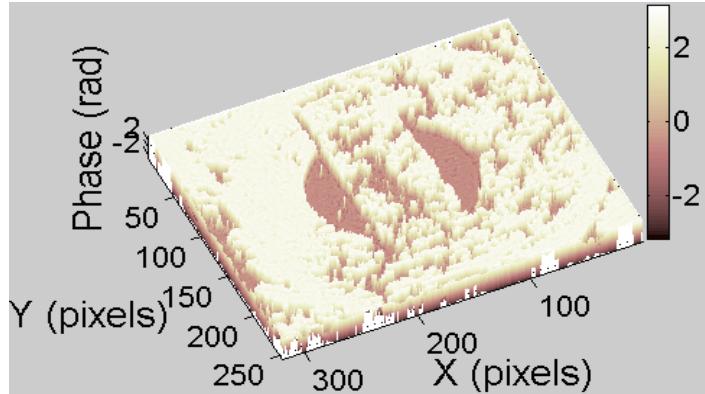


1-2. Reconstruction of two holograms at different wavelengths

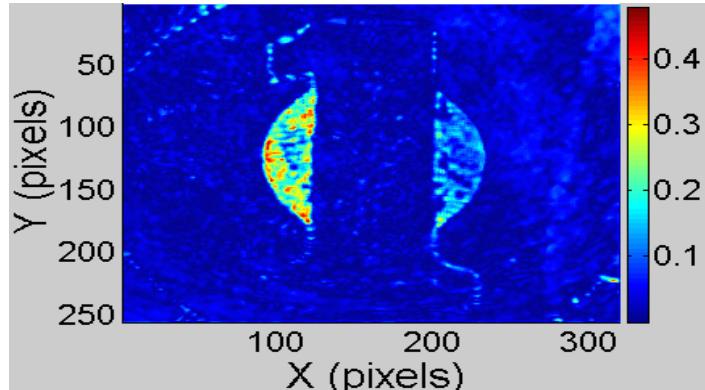
1542.7661 nm



3D Phase

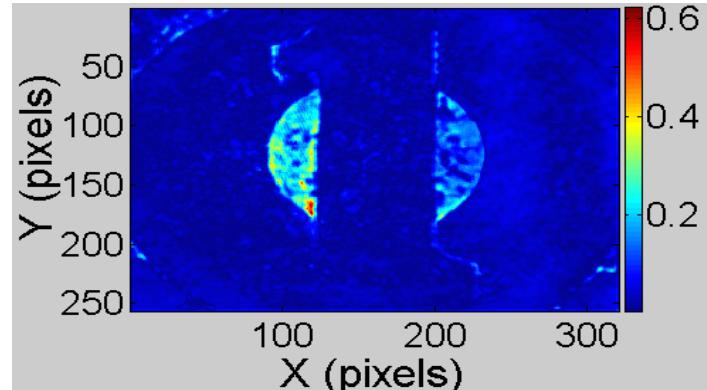
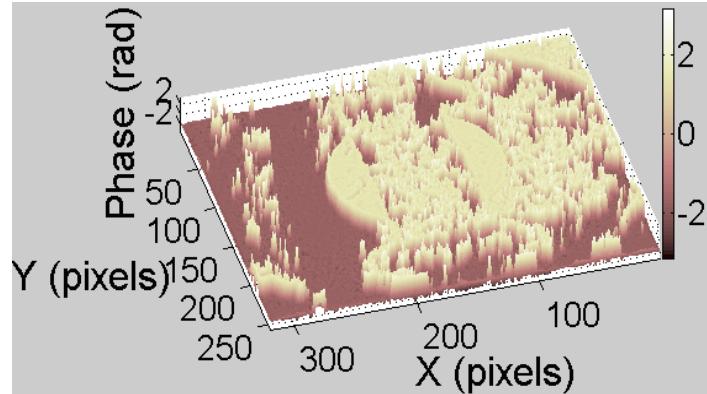
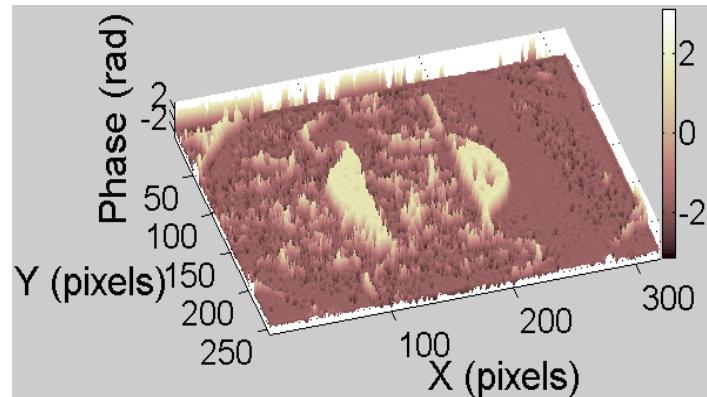


3D reversed
Phase



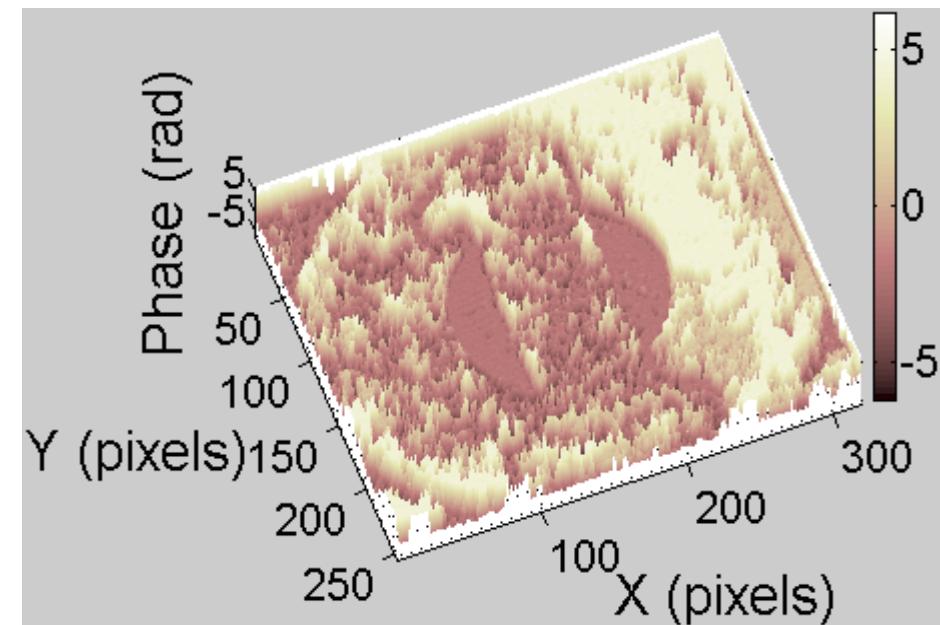
3D Amplitude

1534.8211 nm

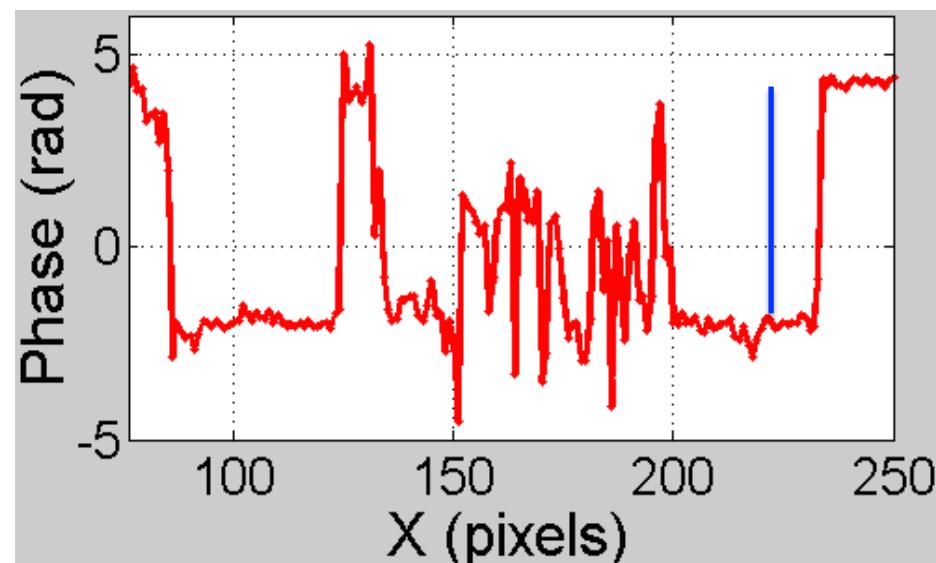
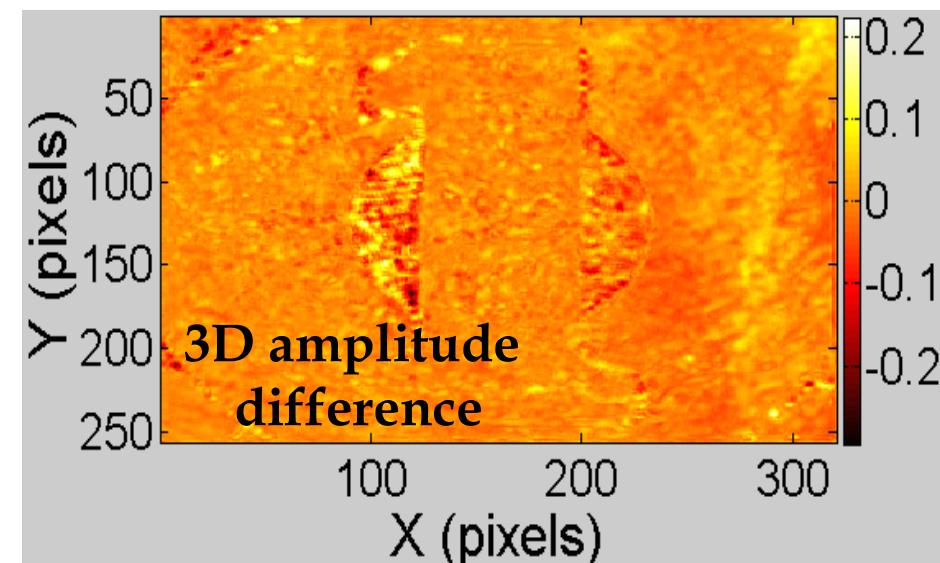
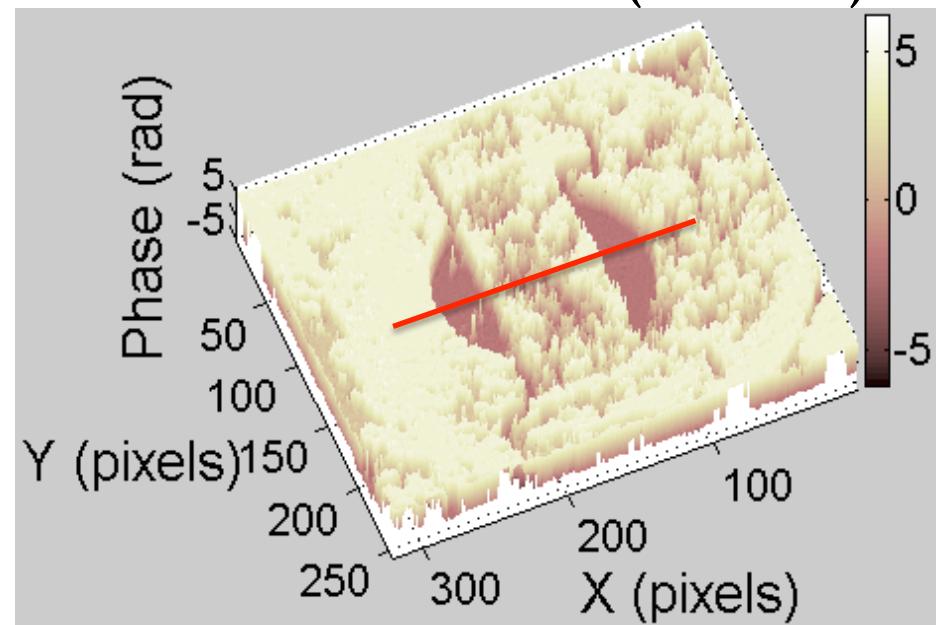


1-2. 3D amplitude and phase differences

3D Phase difference

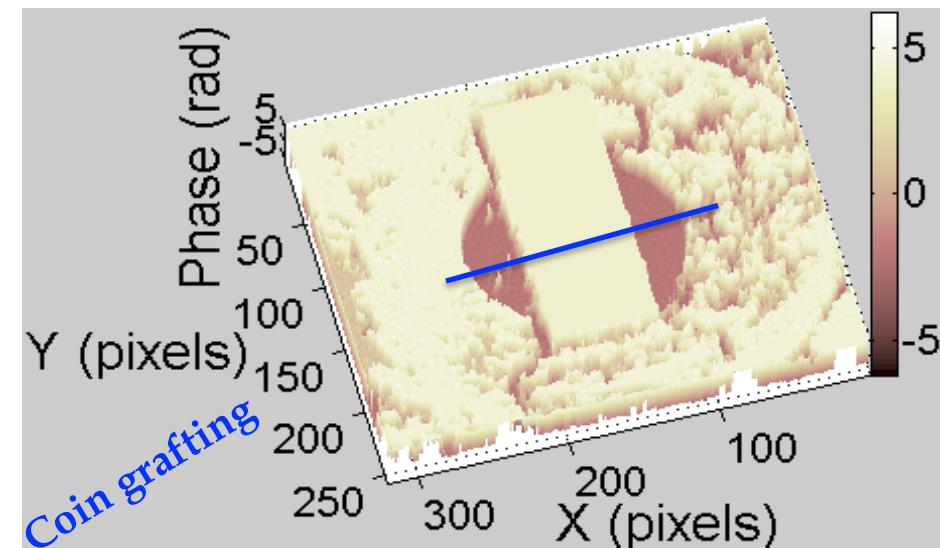


3D Phase difference (reversed)

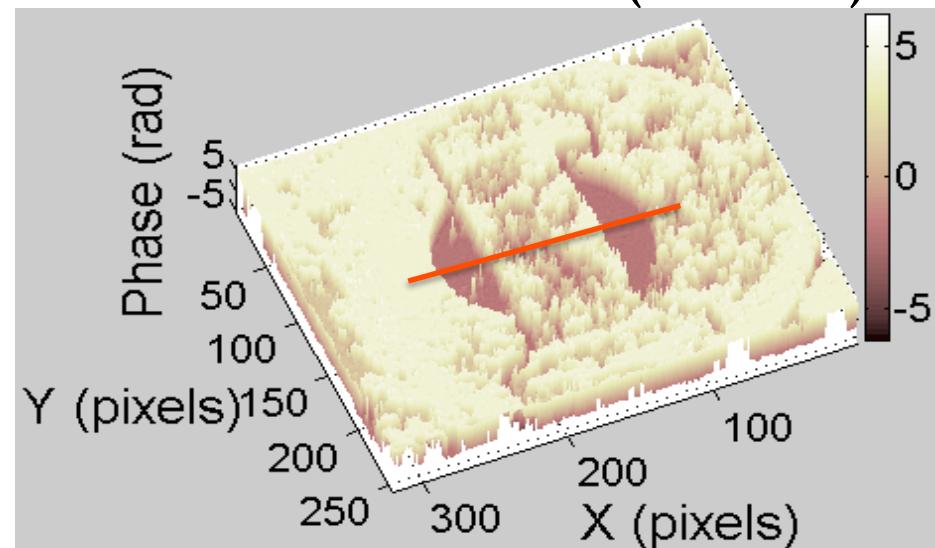


1-2. 3D amplitude and phase differences

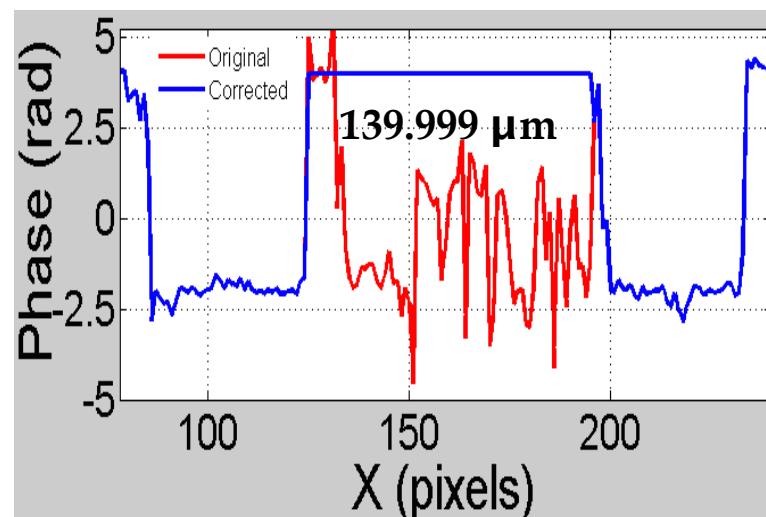
3D Phase difference



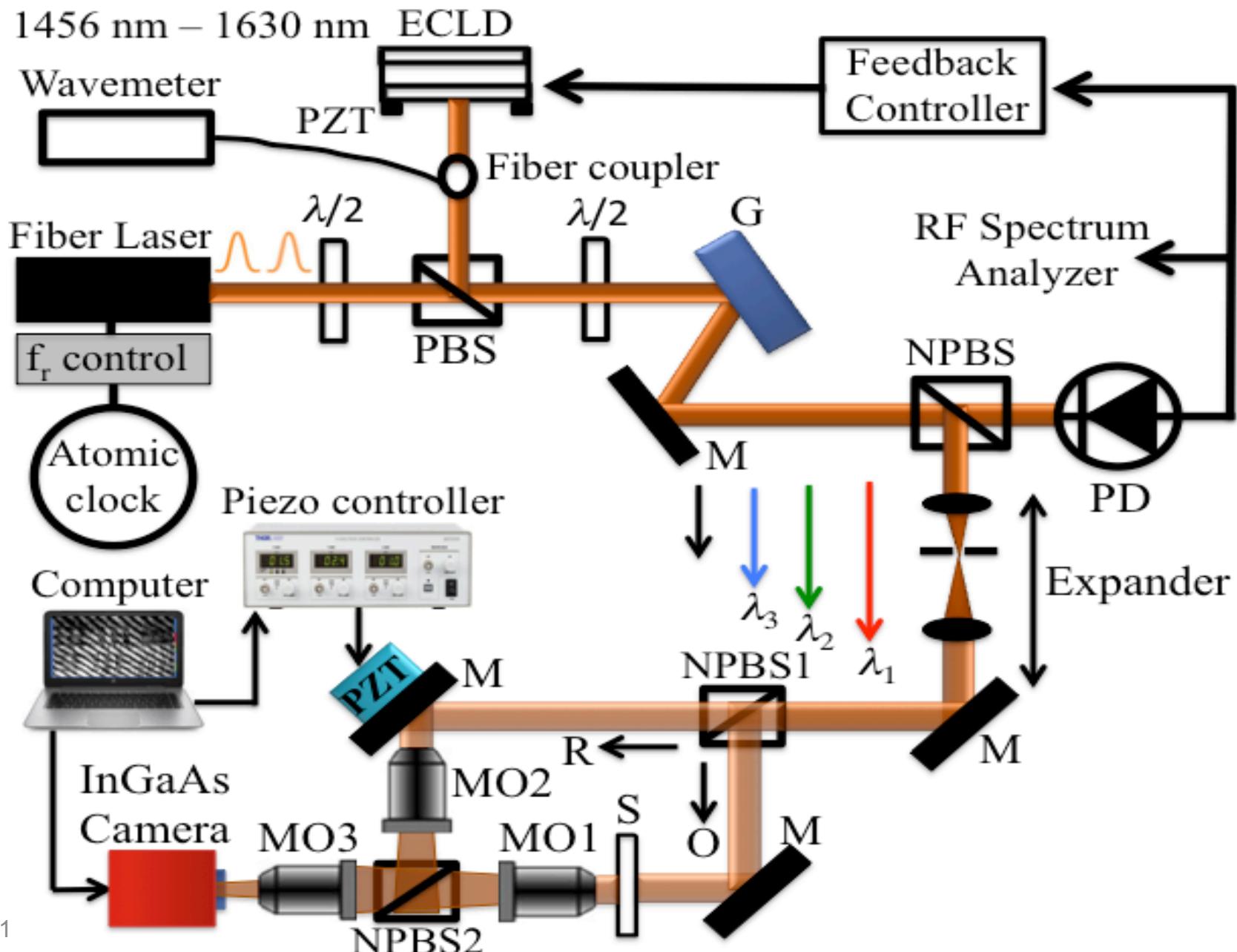
3D Phase difference (reversed)



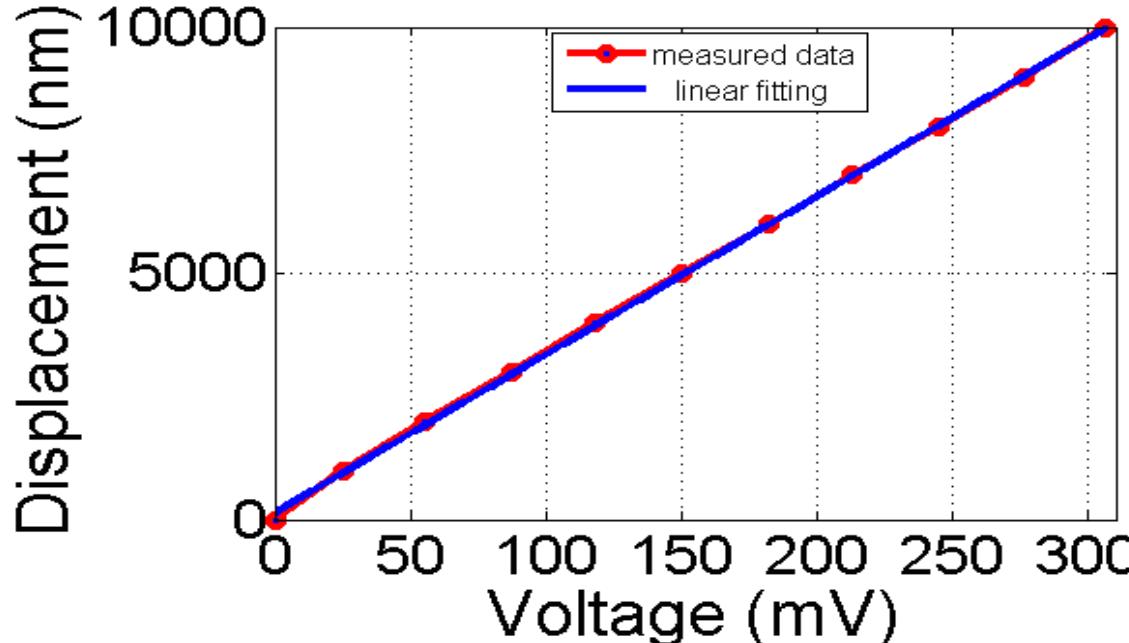
| | Surface height measurement (holography) | Surface height measurement (confocal microscope) |
|---|---|--|
| Apparent wavelength (nm) (1542.7661 & 1534.8211) | 139.999 45 µm | |
| Actual wavelength (+nm) (1542.7657 & 1534.8207) | 139.999 37 µm | 120.00000 µm |
| Actual wavelength (-nm) (1542.7665 & 1534.8215) | 139.999 52 µm | |



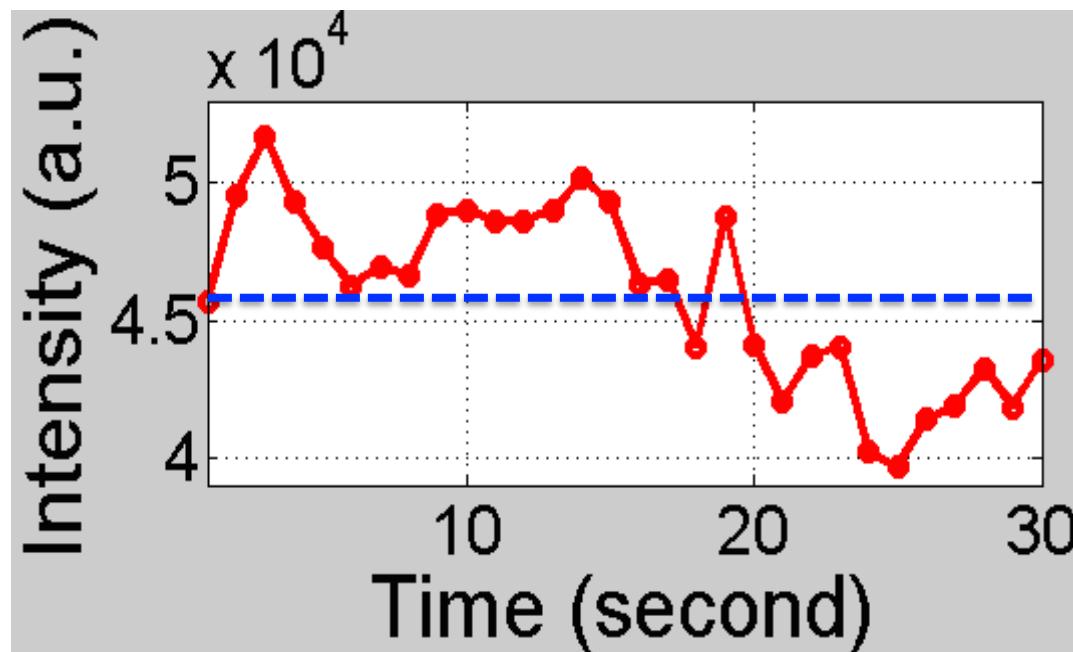
3. Digital holographic microscopy referenced by OFC



3-1. Calibration and impact of ambient vibrations



Voltage (mV)
vs. Disp. (nm)



3-2. USF object (pattern 1)

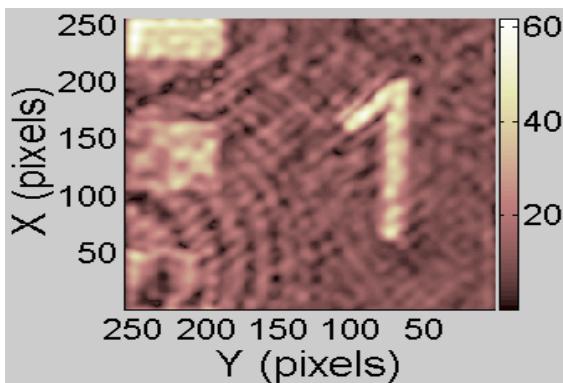
Image (1537.3840 nm)



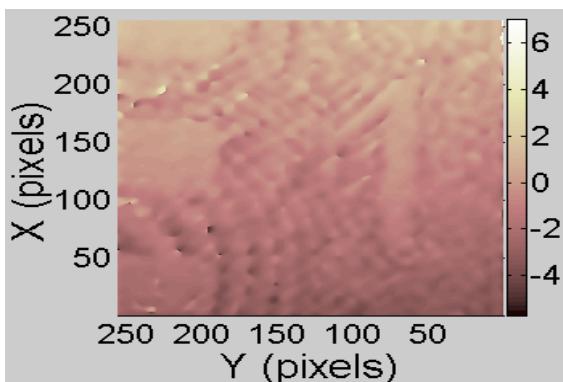
Corrected (1537.3840 nm)



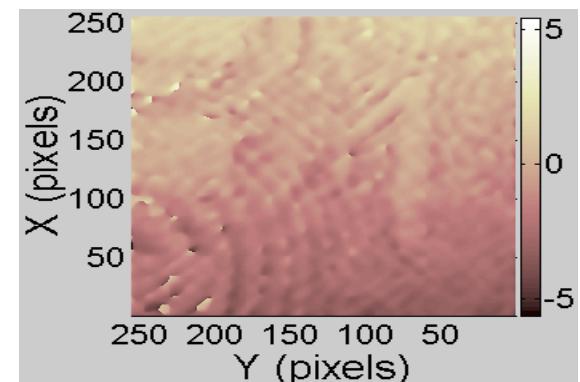
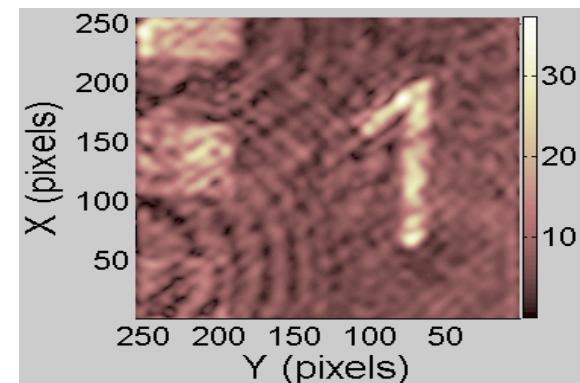
Holograms



3D Amplitude

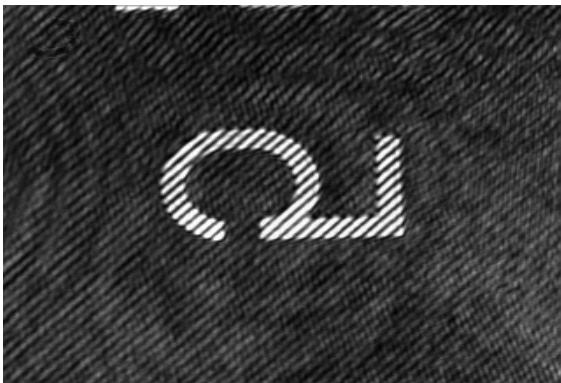


3D Phase



3-3. USF object (pattern 5)

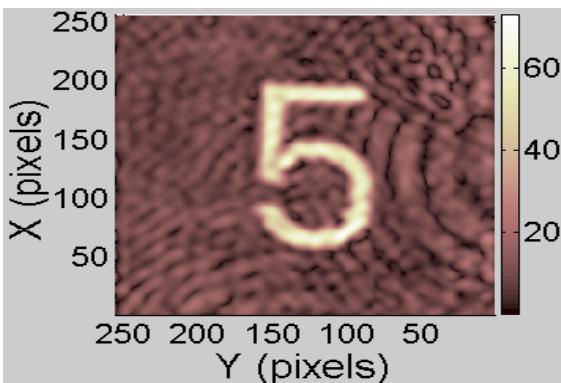
Image (1536.9372 nm)



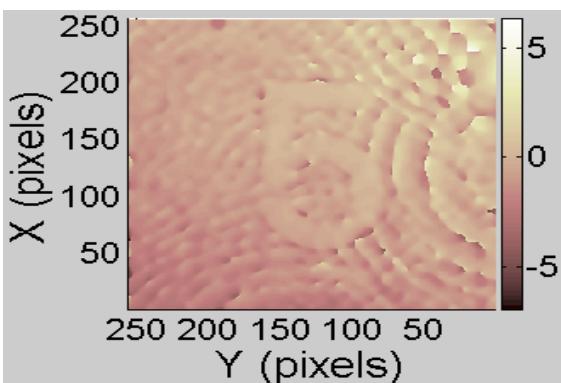
Corrected (1536.9372 nm)



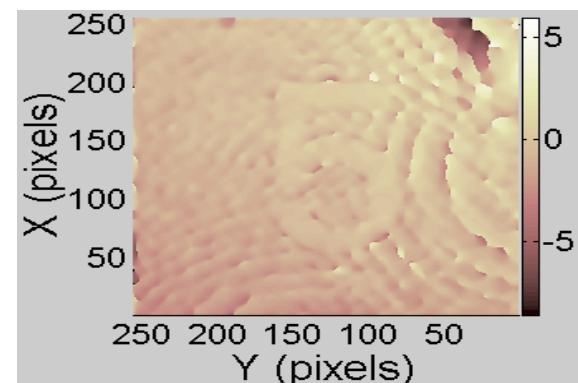
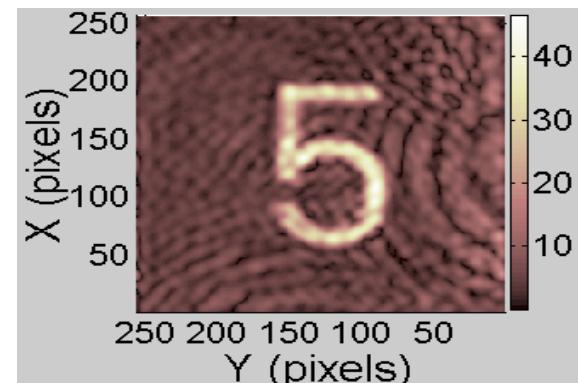
Holograms



3D Amplitude

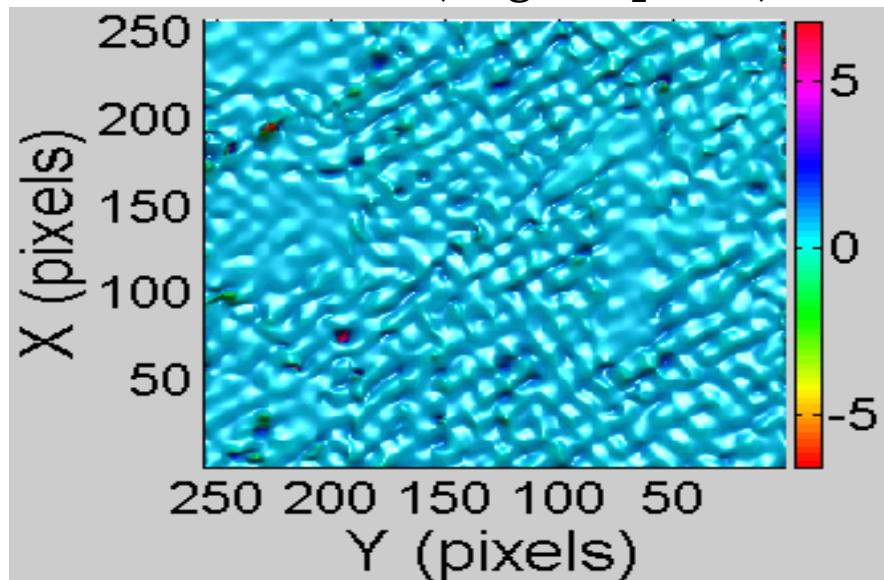


3D Phase

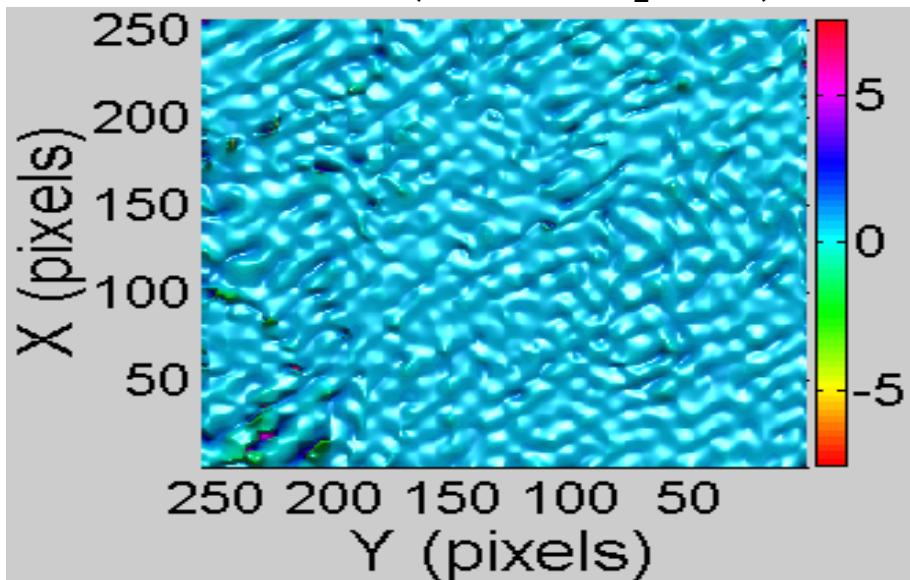


3-2. Phase difference (1537.3840nm - 1537.3845nm)

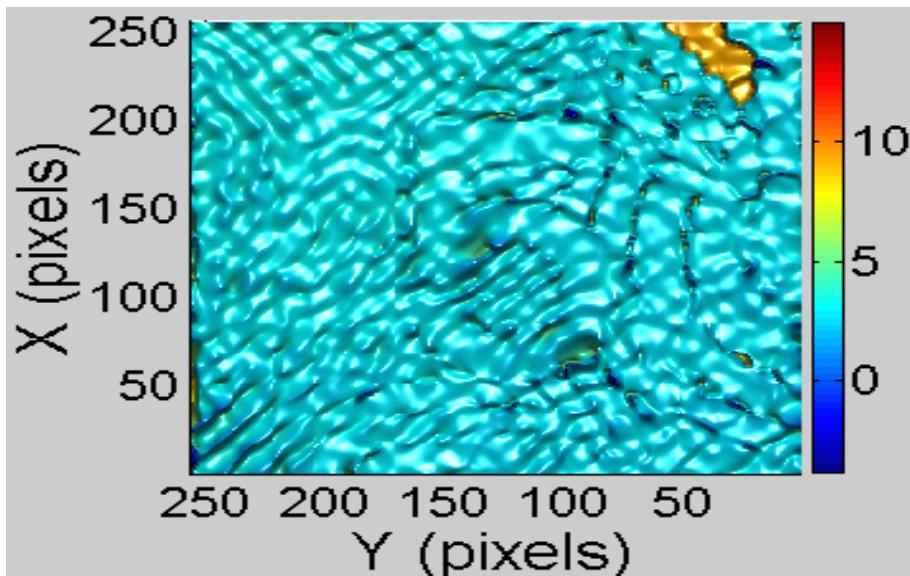
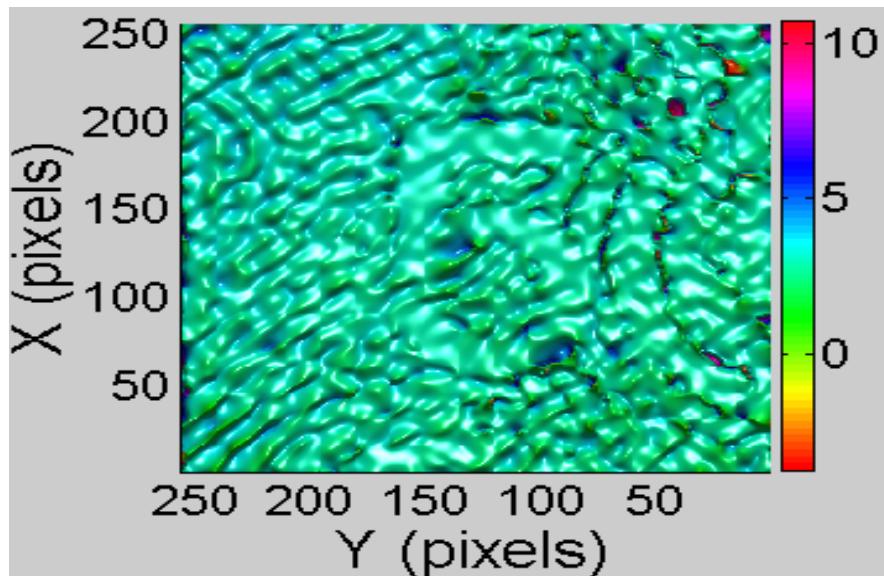
Phase diff (original phase)



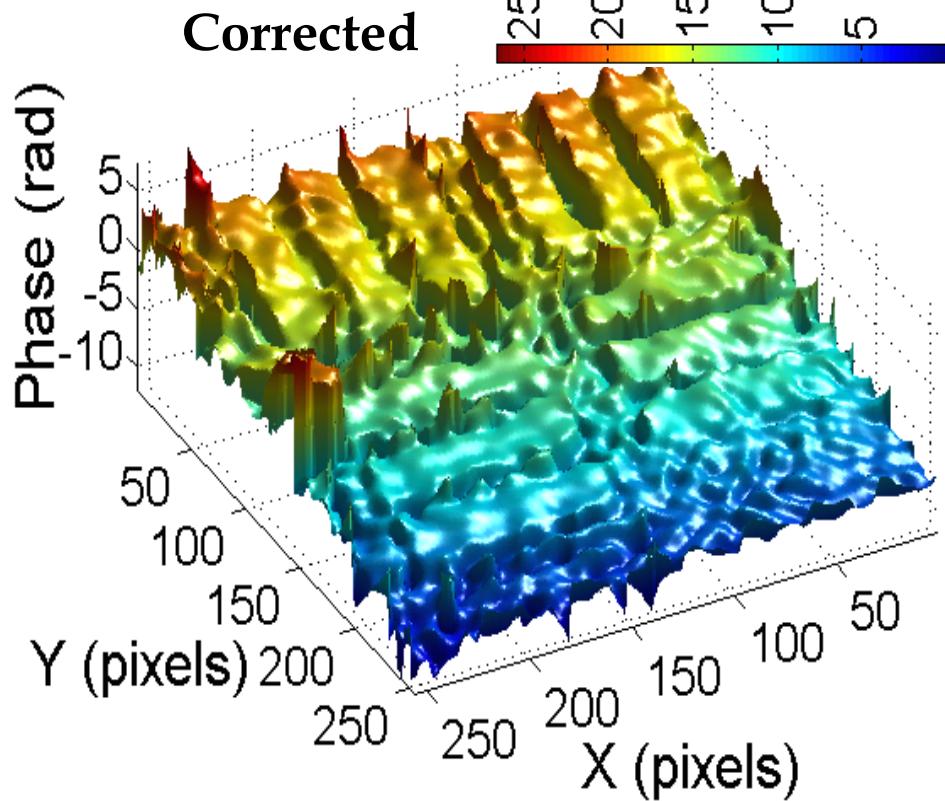
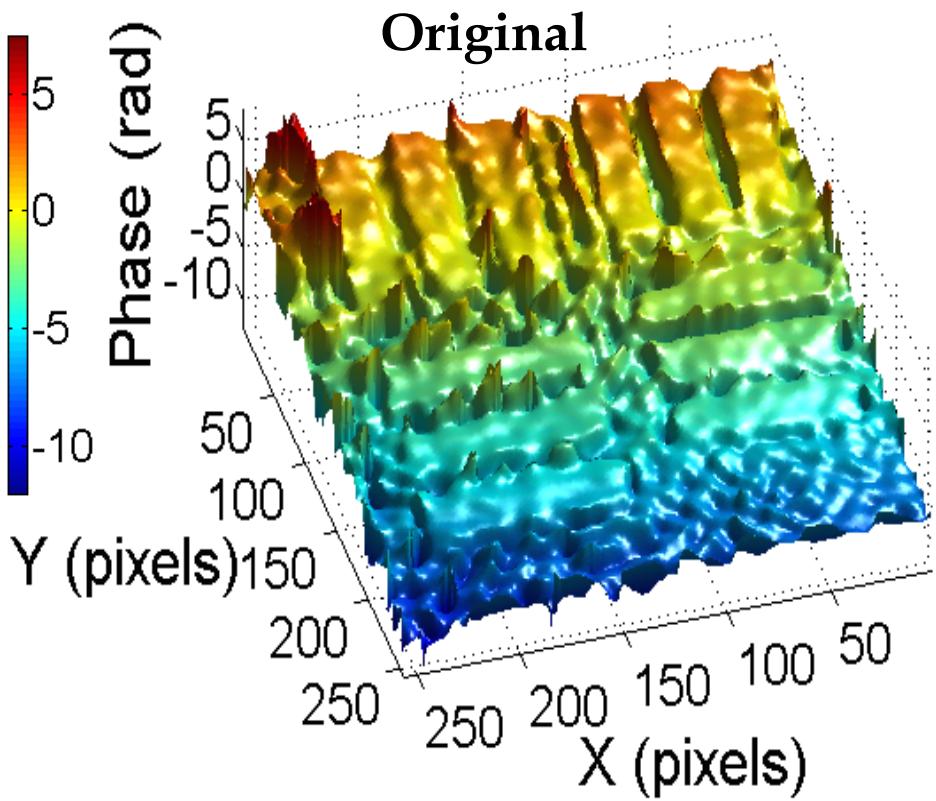
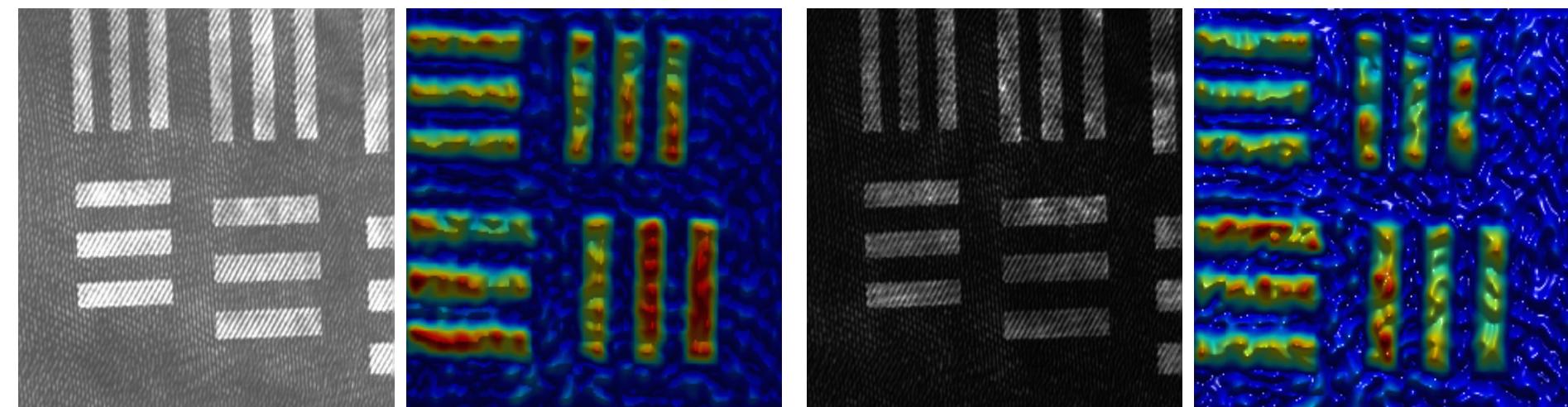
Phase diff (corrected phase)



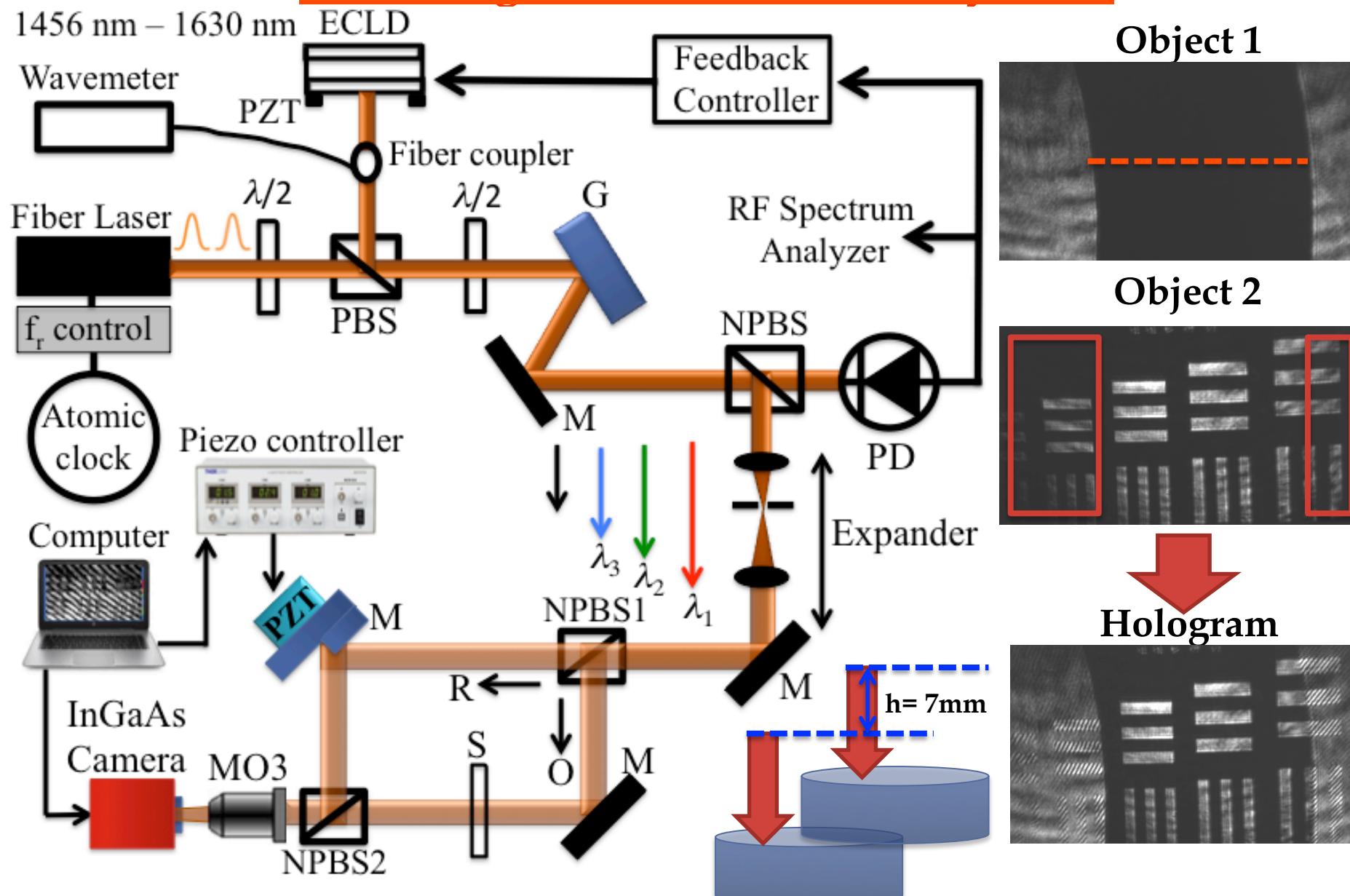
3-3. Phase difference (1536.9372nm - 1537.0236nm)



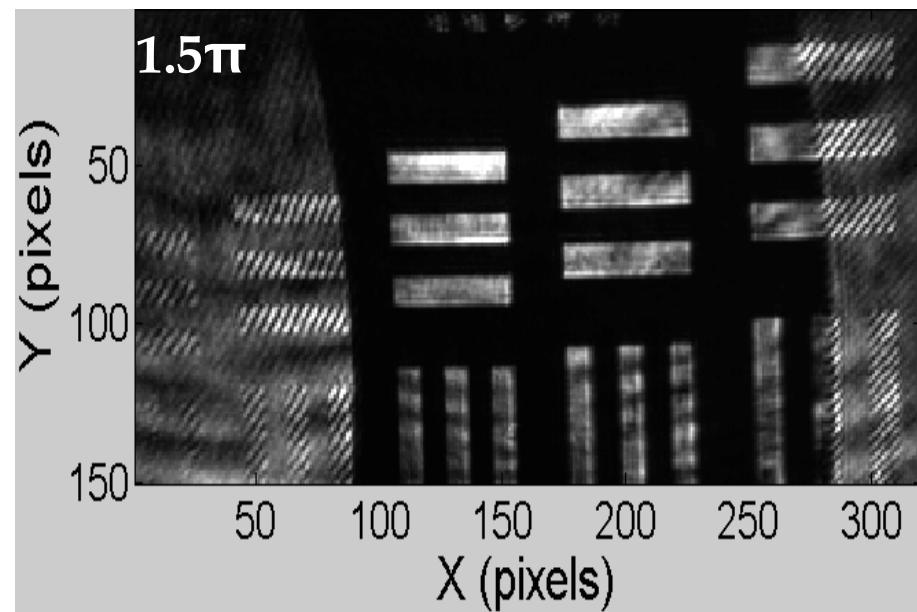
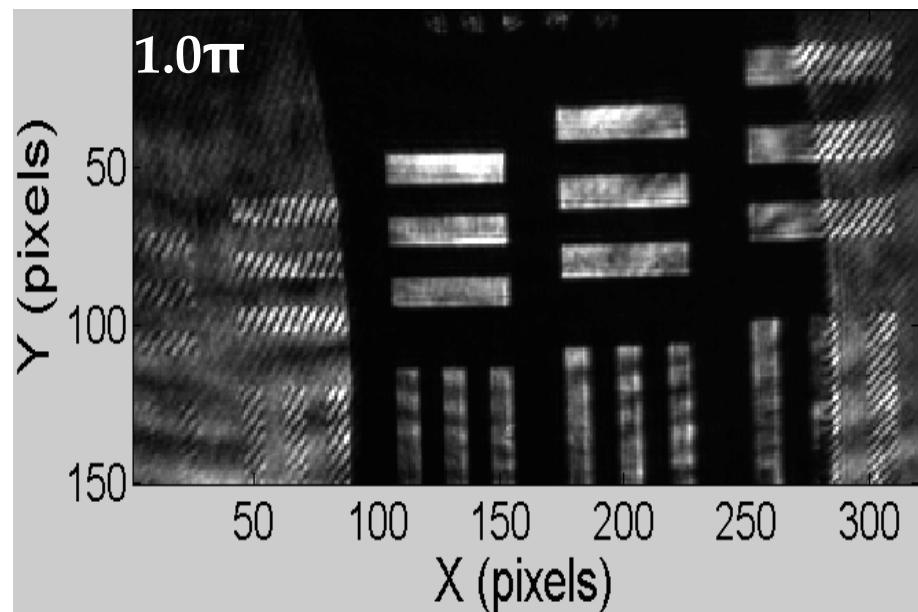
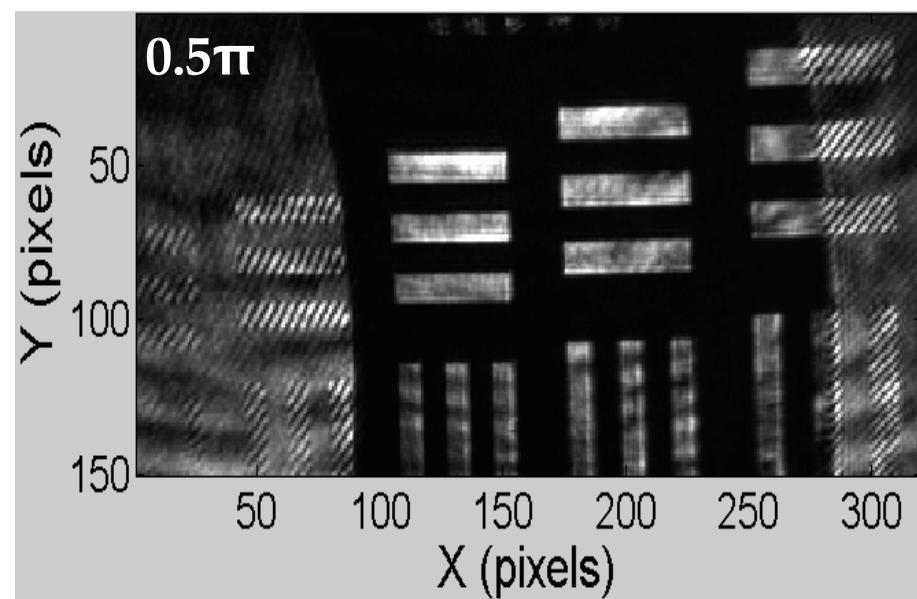
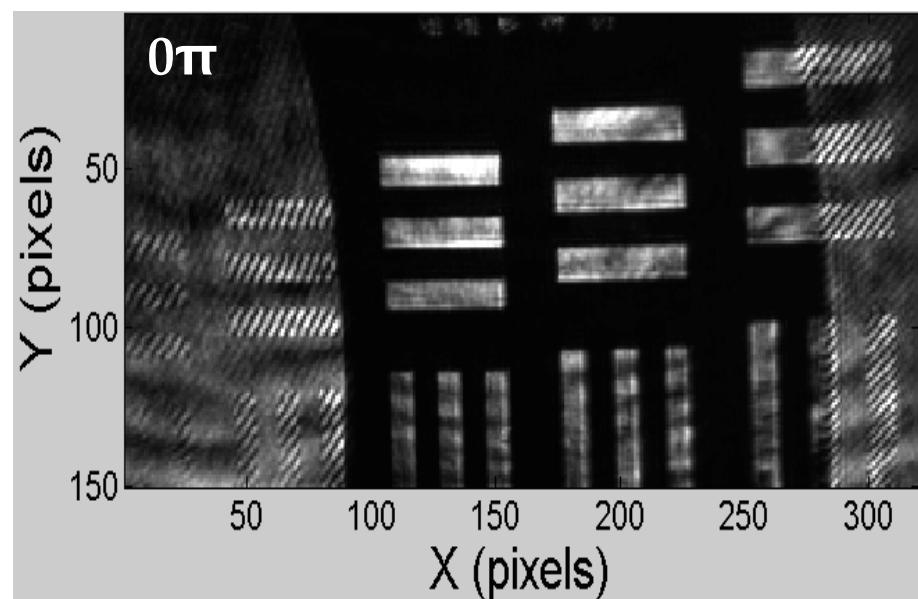
3-4. USF object (some patterns) at 1540.8583 nm



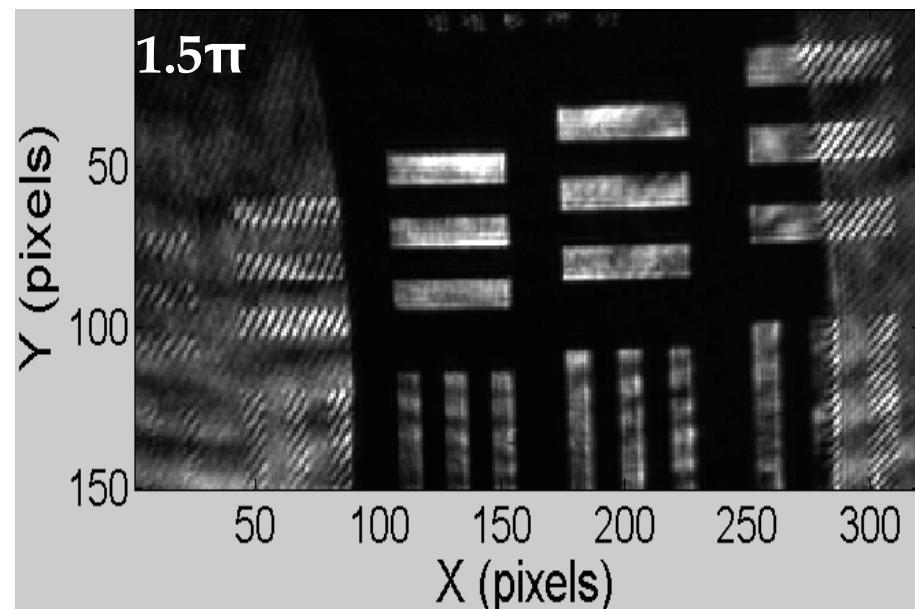
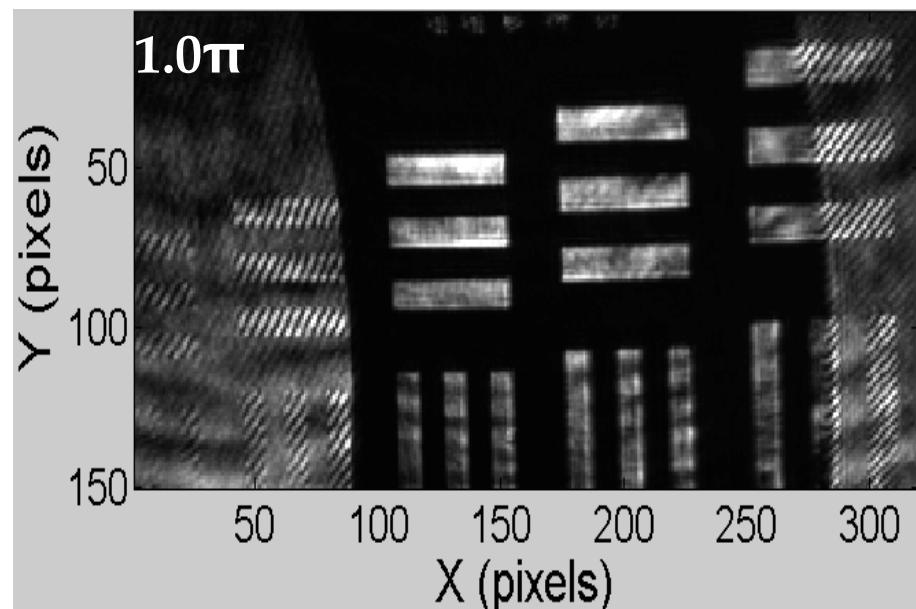
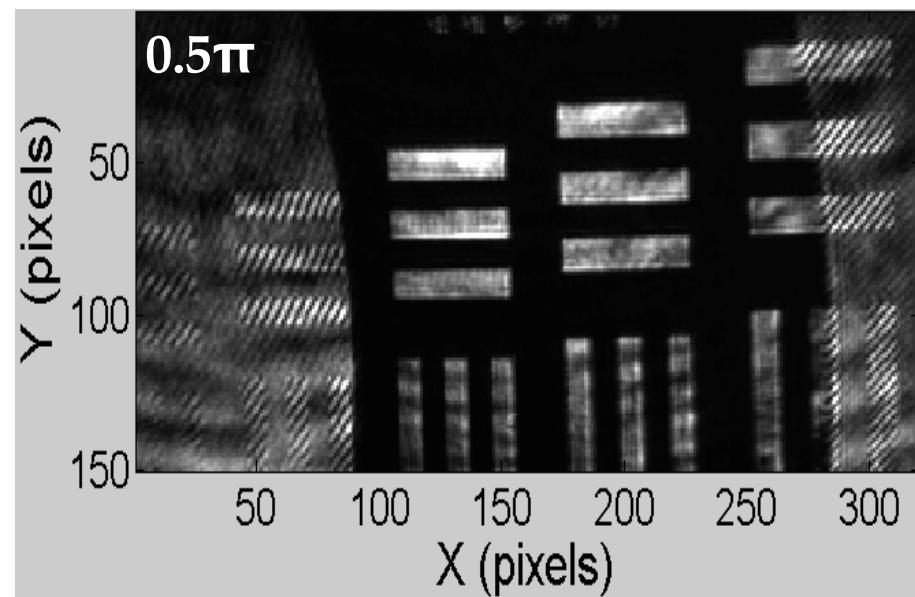
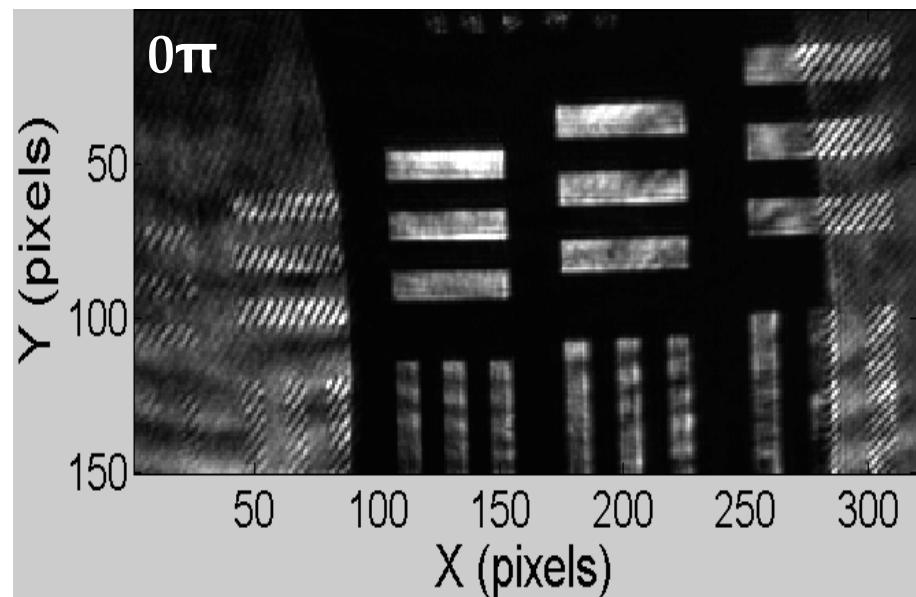
4. High-precision multi-object investigation by multi-wavelength DH referenced by OFC



4-1. Phase shifting (1540.4010 nm)

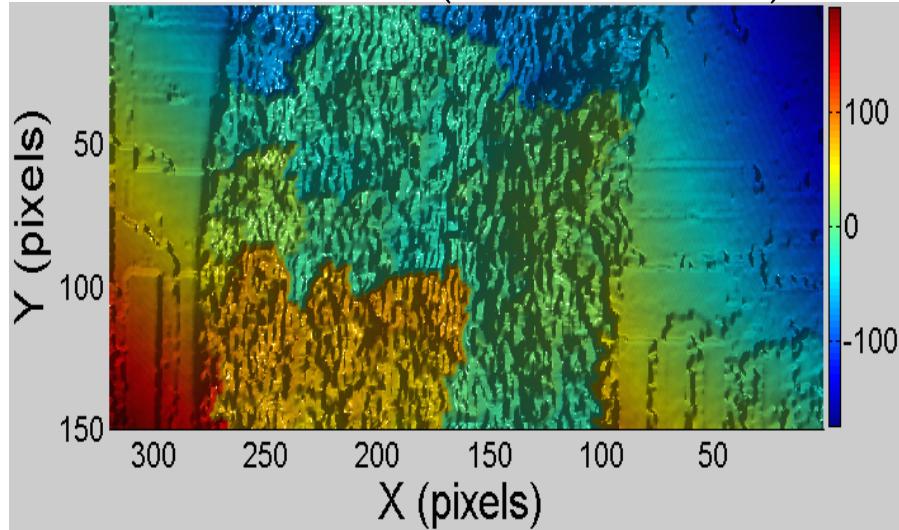


4-1. Phase shifting (1541.4015 nm)

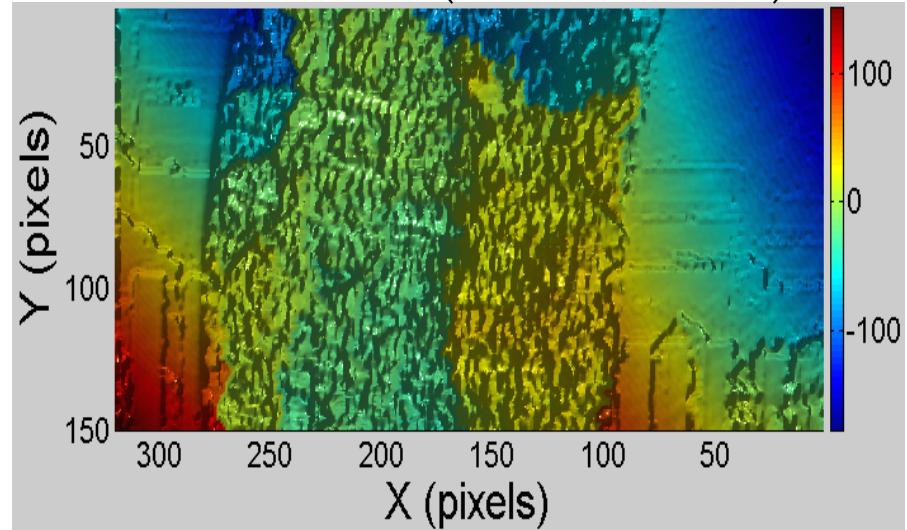


4-1. Reconstruction

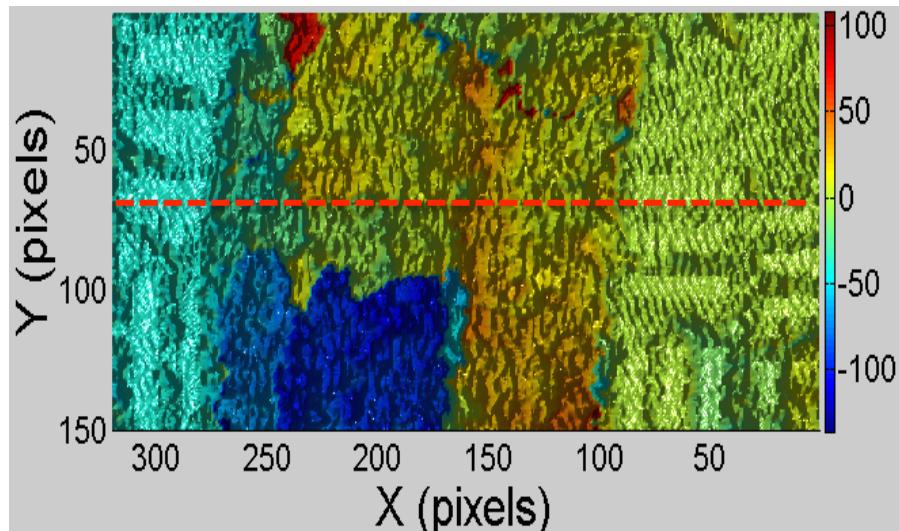
3D Phase at (1540.4010 nm)



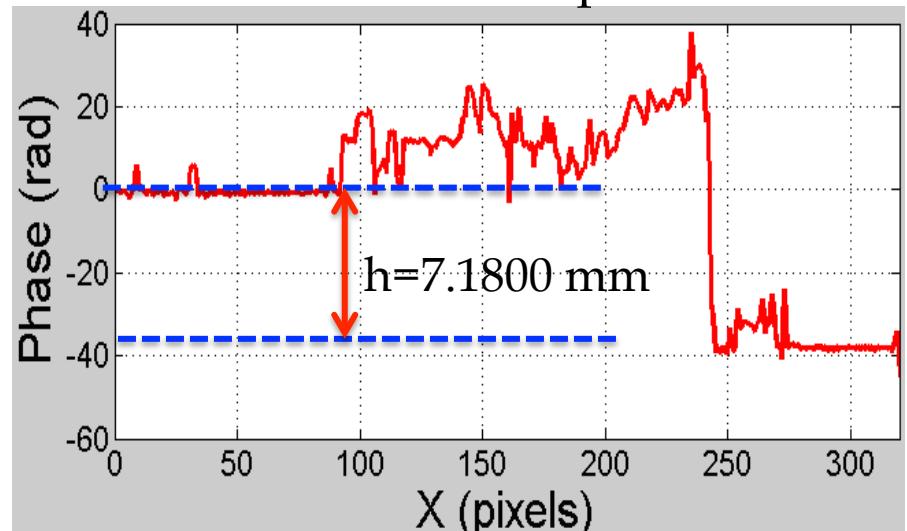
3D Phase at (1541.4015 nm)



3D Phase diff.

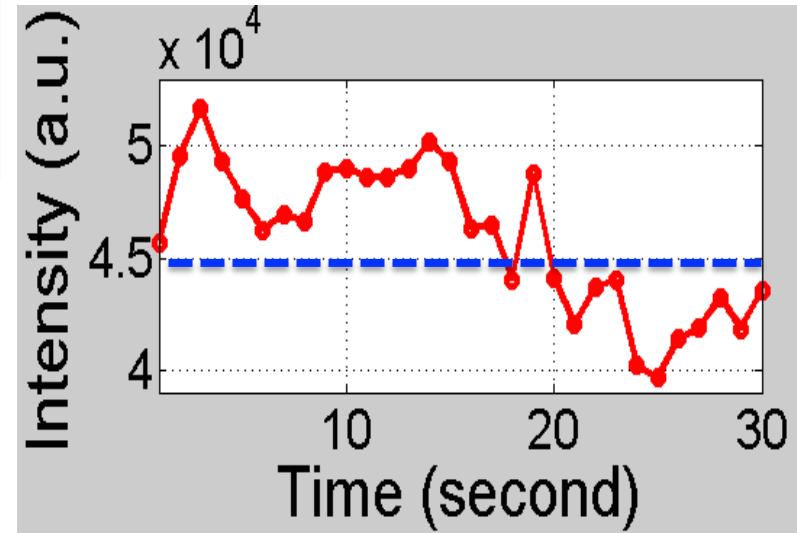
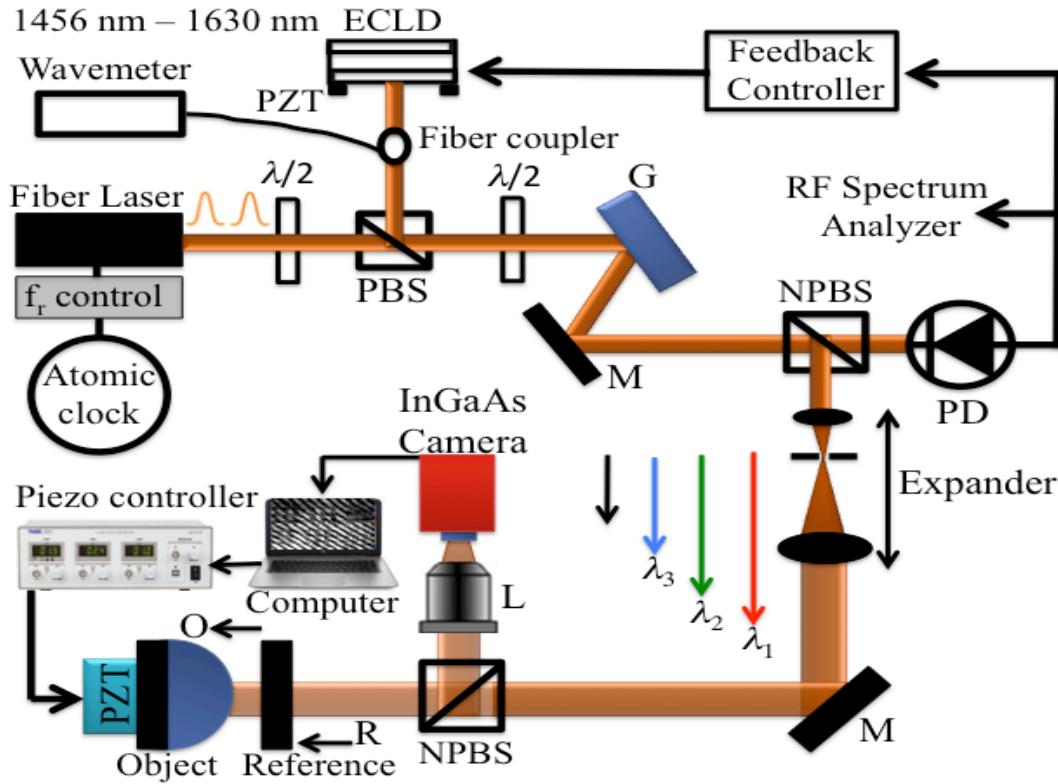
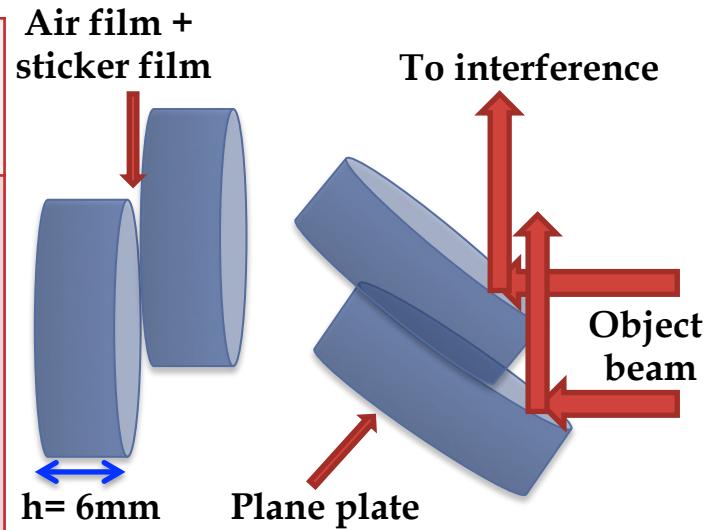


1D Phase diff. profile



4-1. Results and the coming work

| | Surface height measurement (phase-shift) | Surface height measurement (Nominal) |
|--|--|--------------------------------------|
| Apparent wavelength (nm) (1540.4010 & 1541.4015) | 7.1800 32 mm | |
| Actual wavelength (+nm) (1540.4006 & 1541.4011) | 7.1800 29 mm | 6.00000 mm |
| Actual wavelength (-nm) (1540.4014 & 1541.4019) | 7.1800 37 mm | |



Thank you for listening.
Any questions or suggestions?